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Bachelor in Micro and Nanotechnology Engineering

**Multilevel metallization  
scheme using printing technologies for  
IC fabrication using discrete  
oxide TFTs**

Dissertation submitted in partial fulfilment of the requirements  
for the degree of  
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*“When everything seems to be  
going against you remember  
that the airplane takes off  
against the wind not with it.”*

*Henry Ford*

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## Abstract

Despite the emergence of flexible electronics as a technology for manufacturing integrated circuits at lower costs than traditional silicon microelectronics, costly and time-consuming clean room processes are still needed to interconnect the various transistors that make up the circuits. In this context, this dissertation presents an alternative, based on printing processes of multi-layer metallic interconnections, that allow to connect thin film transistors (TFTs) in functional circuit blocks, thus bringing a significant cost reduction and great flexibility for the prototype of new circuits.

For such, a silver ink and polyvinylpyrrolidone (PVP) solution were used to form the conductive and insulating layer respectively. Using an inkjet printer, it was possible to pattern, on glass, silver lines with 100 and 50  $\mu\text{m}$  width and a resistivity of  $7.12 \times 10^{-8} \Omega\text{m}$  using 200 °C for 30 min. PVP was deposited with a thickness of 3.5  $\mu\text{m}$  to ensure insulation between conductive layers and a laser etching process was implemented to create vias between different metallization levels. Finally, the developed process was demonstrated in several digital circuit blocks based on oxide TFTs.

Keywords: Inkjet, Conductive ink, Multi-level metallization, Silver interconnections, Silver lines





## Resumo

Apesar da emergência da eletrônica flexível como uma tecnologia para o fabrico de circuitos integrados com custos mais reduzidos que a tradicional microeletrônica de silício, são ainda necessários processos dispendiosos e morosos de sala limpa para interligar os vários transístores que constituem os circuitos. Neste contexto, apresenta-se uma alternativa baseada em processos de impressão de múltiplas camadas de pistas metálicas que permitem ligar transístores de filme fino (TFTs) em blocos de circuitos funcionais, trazendo assim uma redução significativa de custos e grande flexibilidade para o teste experimental de novos circuitos.

Para tal uma tinta de prata e uma solução de polivinilpirrolidona (PVP) foram utilizadas para formar a camada condutora e isolante respetivamente. Utilizando uma impressora por jato de tinta foi possível padronizar, sobre vidro, a prata em linhas de 100 e 50  $\mu\text{m}$  com uma resistividade de  $7.12 \times 10^{-8} \Omega\text{m}$ , utilizando 200 °C durante 30 min. Entretanto, o PVP foi depositado com uma espessura de 3.5  $\mu\text{m}$  de forma a garantir o isolamento entre camadas condutoras, sendo ainda implementado um processo de erosão por laser criando vias entre diferentes níveis de metalização. Por fim, os processos desenvolvidos foram demonstrados em vários blocos de circuitos digitais, baseados em TFTs de óxidos.

Palavras-chave: Impressora por jato de tinta, Tintas condutoras, pistas condutoras de prata, impressão de múltiplas camadas, interligações de prata



## List of acronyms

TFT - Thin film transistor  
PE - Printed electronics  
R2R – Roll to roll  
Ag - Silver Ag  
DOD - Drop on demand  
CIJ - Continuous inkjet  
NP - Nanoparticle  
CNT - Carbon nanotube  
IR - Infrared  
UV - Ultraviolet  
DPI - Drops per inch  
PVP - Polyvinylpyrrolidone  
RGB - Red, green and blue  
PPI - Pulses per inch  
DC – Direct current



## List of symbols

m - Meter  
nm - Nanometer  
 $\mu\text{m}$  - Micrometer  
 $^{\circ}\text{C}$  - Degrees Celsius  
cm - Centimeter  
mm - Millimeter  
s - Seconds  
V - Volts  
mV - Millivolts  
mA - Milliampere  
 $\Omega\text{m}$  - Ohm meter  
 $\Omega$  - Ohm  
mm/s - Millimeter per second  
% - Percent  
wt% - Percentage in weight  
GHz - Gigahertz  
cP - Centipoise  
pL - Picoliter  
mL - Millilitre  
g - Grams



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## Motivation and objectives

Traditionally electronic devices are mainly fabricated using a subtractive approach, that involves processes like photolithography and vacuum-based techniques. These techniques consists of multi-step processes, require specialized equipment and facilities and utilize hazardous materials, which translate to higher cost of production and time-consuming process. For this reason, it is starting to appear a need for a new approach to combat those problems and satisfy the market needs for simpler and cheaper manufacturing.<sup>1-3</sup>

This new approach is completely focused on additive processes and techniques, where the material is deposited directly on the desired spot, like inkjet printing and other types of printing techniques. Allowing the emergence of printed electronics, that in the past few decades has gained a lot of interest due to its massive flexibility and simplicity of production, for its one-step process. Many different materials and substrates can be used, giving it a wide range of possible applications compatible with industrial manufacturing. This solution allows a fast production rate with less waste, lowering its overall cost. Due to this kind of advantages the practical applications, that can arise from the use of this techniques are endless and constitute a very attractive and interesting area of investigations for this work. The consequences can be showed by the fact that the market is projected to reach \$ 26.6 billion by 2022 from the current \$ 14 billion in 2017 at a compound annual growth rate of 13.6 %.<sup>1-4</sup>

The purpose of this dissertation is to apply a set of low-cost, simple and rapid hybrid techniques to develop a multilevel metallization scheme useful to fabricate integrated circuits from discrete oxide thin film transistors (TFTs). The goal is to use different printing techniques to deposit, on a glass substrate containing high-performance, clean room fabricated oxide TFTs, multiple levels of conductive layers of silver (Ag) interconnections with line width as small as possible (sub-100  $\mu\text{m}$ ), with each level electrically insulated using printed insulating polymers.

To accomplish this goal, the following sub-objectives will be addressed:

- i) Understanding the mechanisms and a first optimization of the printing process on regular glass and over the polymeric insulating layer.
- ii) Optimization of the sintering process to convert the ink to conductive interconnections.
- iii) Via formation through the insulator to connect the different levels of conductive layers, by laser ablation
- iv) Comprehensive morphological and electrical characterization of the printing interconnections and insulating layer.
- v) Final prototype fabrication and characterization comprised of several digital circuit blocks (NAND gate, a simple inverter and an inverter with 2 and 3 drive TFTs in parallel) using two levels of printed conductive layers.





## 1. Introduction

### 1.1 Printed electronics

Nowadays electronic components can be made using two different approaches: i) the conventional and widely used silicon-based microfabrication, that involves subtractive processes and techniques; ii) an additive process which gives rise to an area called printed electronics (PE).<sup>1,2</sup>

PE is an area of electronics that focus on fabricating devices by using material deposition techniques, like conventional printing techniques<sup>5</sup> and in the last few years it has received enormous attention for being a potential alternative to the conventional approach.<sup>6,7</sup> This is justified through to low-cost manufacturing with high throughput<sup>8</sup>, ease of integration, rapid prototyping<sup>2,9,10</sup> and compatibility with flexible systems (e.g., large area-electronics and hybrid system fabrication on different substrates, organic or inorganic). This contrasts with classic microfabrication techniques, such as photolithography, laser ablation<sup>2</sup> and vacuum-based techniques, that typically require complicated manufacturing processes with a significant number of steps, time bottlenecks in the prototyping and development stage. The disadvantages of these techniques are reflected in the downtime without any production, excessive material waste, high environmental impact and high production costs.<sup>1-4,6,10-14</sup>

This additive approach uses as building blocks conductive materials such as metal nanoparticles and nanowires, carbon nanotubes and graphene to fabricate transparent conductive films, flexible energy harvesting and storage devices, TFTs, electroluminescent device and wearable sensors, are some examples.<sup>1,7,8,15</sup> All of these devices require some type of conductive structures and good alignment between layers, which means that highly conductive patterns with a high resolution are a critical component of PE which are sometimes hard to achieve.<sup>4,11</sup>

### 1.2 Printing techniques and inkjet printing of conductive lines

Printing techniques can be divided in two categories: i) Noncontact techniques or nozzle-based patterning; ii) contact-based patterning. The noncontact techniques include inkjet printing, electrohydrodynamic (EHD) printing, aerosol jet printing and slot dye coating. Screen printing, gravure printing and flexographic printing are examples of contact techniques, that nowadays are the technique employed for mass printing.<sup>2,4,11</sup>

Contact printing techniques require the printing pads to be in contact with the substrate in order to transfer the inked patterns to the substrate. They typically use an embossed or engraved roll to transfer the ink to the substrate, the major problems being the potential damage induced to the bottom layer during printing and longer set-up times which usually translate into increased initial costs. In contrast, the non-contact techniques, don't require a mask to deposit the ink, instead eject ink from a nozzle and the nozzle itself never gets in contact with the substrate. Therefore contaminations and wastages are minimal but nozzle clogging and unwanted ink spread are still problems to be addressed, due to the fact that a clogged nozzle prevents the ink from coming out (hindering the printing process) while unwanted ink spread limits the resolution of the technique.<sup>2,11</sup> In general, most of these techniques benefit from the fact that the user controls where and how much material is deposited, eliminating the need for etching processes.<sup>10</sup>

#### 1.2.1 Inkjet

Inkjet printing is a deposition technique for printing a wide range of functional materials.<sup>15</sup> These materials in the form of colloidal dispersions are deposited through the micron-sized printing nozzle, with the advantage of being extremely accurate<sup>9</sup> and conformal<sup>16</sup> over large areas at a fast speed and low cost<sup>17</sup>. Additionally, small amounts of materials can be deposited (picolitre size drops in the range of 20-50  $\mu\text{m}$ ,<sup>11</sup> depending on the nozzle diameter<sup>3</sup>) with minimal waste and over rigid or flexible substrates.<sup>1,3,5,8,13,18-20</sup> Moreover, as this is a noncontact and maskless deposition technique,<sup>20,21</sup> resulting in minimal damage to the substrate and allows for the deposition of different materials in the same substrate<sup>4,16</sup> resulting in minimal contaminations from previous printing processes.<sup>2,13</sup>

There are two main mechanisms for the printing head to generate droplets: drop on demand (DOD) printing, which is the most utilized printing mechanism and it is the selected one for this work. The other mechanism is the continuous inkjet (CIJ) printing<sup>3,13,22</sup>. These systems are now robust industrial tools and are used for high-speed graphical applications.<sup>1,4,9-11</sup>

The DOD mode, in contrast to CIJ, is characterized by a smaller droplet size, efficiency of material usage and higher accuracy.<sup>3,13,14</sup> The droplets are ejected by a pressure pulse generated in a chamber filled with ink behind the nozzle.<sup>3,13,14,22</sup> This pressure can be generated either by thermal pulse, a piezoelectric actuator or by an electrostatic pulse (Attachment A).<sup>2,4</sup> In the first one the heating resistor receives the signal to start heating up and vaporise the ink to generate the vapour bubble that in turns pushes the ink out of the nozzle. In the piezoelectric mode the deformation of the piezoelectric ceramic actuator, due to an application of an electric signal, induces a pressure wave within the ink chamber to dispense the ink droplet out of the nozzle. Finally, in electrostatic mode, the electrostatic interaction, due to a potential difference between the conductive ink and an intermediate plate coupled to the substrate holder, forces the ink to be ejected from the nozzle.<sup>2,10,11,13,22</sup>

The CIJ is characterized by the fact that the nozzle is continuously ejecting ink droplets and to control the position of each droplet the printer uses electrostatic forces to deflect them to the desired position on the substrate.<sup>22</sup> In the case of binary deflection CIJ printing, which is one of two printing modes, the droplets are either charged, which end up deflected to the gutter, or uncharged, which makes their way to the substrate. For the multi-deflection CIJ printing, individual droplets have different charges and when this droplets pass through a fixed electric field they are deflected in multiple-directions.<sup>2</sup>

One big problem with all these systems is the possibility of aggregation, that leads to clogging of the printing nozzle, being proper ink selection one way to solve this.<sup>11,20</sup> To help the printing process the ink should have properties within the range accepted by the printer, nevertheless, the tuning of the printing parameters also helps with this. Particle size, viscosity, surface tension and density of the ink all play an important role in the droplet formation and ejection.<sup>3,4,6,18,23</sup> In this work the use of a commercially available ink facilitates setting all these parameters in their correct range.

Another important part of inkjet printing is the interactions of the ink with the substrate. When a liquid drop impacts the substrate there will be a period when the drop shape will be controlled by fluid properties, where surface tension and contact angle play an important role, prior to solidification. Given that normally the deposition process involves more the one droplet, the spacing of those droplets and the speed at the printing head moves are important parameters to consider because this together with the ink properties are the most responsible for the pattern morphology as seen in the Figure 1.1.<sup>3,5,9,15,22</sup>

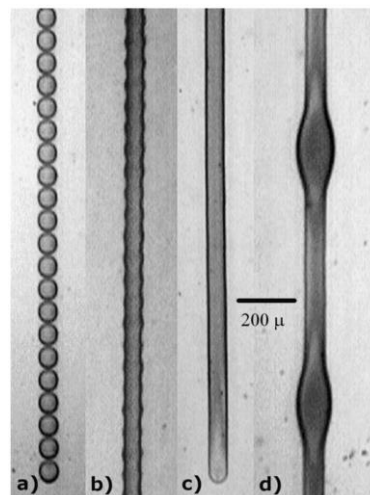


Figure 1.1-Effect of decreasing the drop spacing on the printed line morphology. a) has the biggest drop spacing while d) has the lowest drop spacing.<sup>9</sup>

Typically inkjet printed lines have features size of tens to hundreds of micrometres, with the limit so far being around 30  $\mu\text{m}$ ,<sup>22</sup> and thickness in the range of hundreds of nanometres and from a macroscopic point of view, the type of morphology obtained will influence the electrical performance.<sup>5</sup> To achieve low resistivity, the printed lines should be uniform with a large cross-sectional area. For that end, many facts like substrate surface energy, ambient conditions and printing parameters have some influence. Another important fact that helps the achievement of low electrical resistivity of the lines is the sintering conditions, which will be discussed in section 1.3 of this chapter.<sup>5</sup>

Since the inkjet process deals with colloidal dispersions, solvent evaporation dynamics are essential to take into account because it leads to a common effect called the coffee ring effect. This effect originates from the capillary flow induced by the different evaporation rates across the droplet.<sup>9,24</sup> When a droplet has a pinned three-phase contact line, the excess solvent lost at the edge is replaced by solvent from the centre, leading to a radial capillary flow and a loss of cross-sectional area.<sup>4,24</sup> This effect is highly temperature dependent in a way that the higher the temperature during printing, drying or sintering the more the solvents will evaporate, enhancing the coffee ring effect, leading to narrower widths but a deep valley starts appearing as Figure 1.2 shows.<sup>5,24</sup>

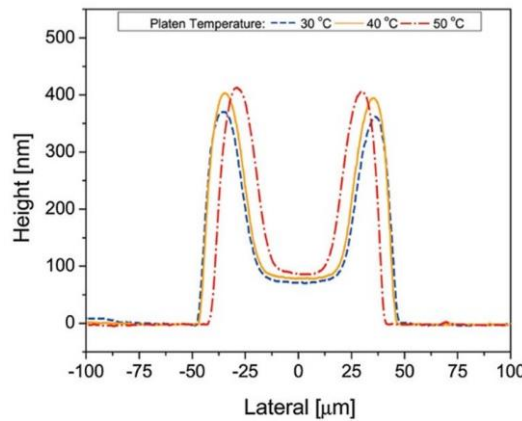


Figure 1.2- Cross-sectional profile of uniform lines printed at different temperatures.<sup>5</sup>

Is important to suppress this effect because it directly affects the morphology of the printing patterns, which in terms affects the resolution of the pattern and consequentially the performance of the device by interfering with the resistivity. There are several ways to reduce the coffee ring effect, like ink-drying on a smooth substrate or by constraining the evaporation at the edge, electrowetting or drying droplets in electric fields, a mixture of two or more liquids with different vapour pressures and surface tension or a sufficiently fast increase in viscosity after deposition.<sup>4,5</sup>

Another important effect that can happen during the printing process is the formation of internal or external cracks in the printed patterns. This can happen due to the large reductions of volume during the evaporation of the solvent, resulting in degraded electrical conductivity by introducing defects, which makes it difficult for the current to flow through the pattern.<sup>23</sup> One way to control this effect is to select a substrate with a coefficient of thermal expansion closer to the metal in the ink.<sup>23</sup>

To achieve the best electrical performance it is useful to understand which variables affect the resistance of a printed line, as shown by the following equation:

$$\rho = \frac{R \times A}{l}$$

Where  $\rho$  is the material resistivity ( $\Omega\text{m}$ ),  $R$  is the resistance ( $\Omega$ ) of the line,  $l$  is the length (m) and  $A$  is the cross-sectional area ( $\text{m}^2$ ). From the equation, it is easily understood that the cross-sectional area needs to be maximized to ensure that the printed material's resistivity is as close as possible to its typical bulk value. Since increasing the linewidth hinders high-density integration, increasing the thickness seems to be the most viable route, provided that transparency of the lines are not a requirement. This can be done simply by repeating the printing process several times,

increasing the thickness layer by layer. Nevertheless, this multi-step printing might also result in an increase of the linewidth so, in the end, the line resistance optimization has to be approached in a way that benefits the application in mind.<sup>5</sup>

Another characteristic of inkjet printing is the ink itself and the properties it should have to achieve a good printability. Conductive inks are multi-component systems containing a conducting material in a liquid medium, that can be aqueous or organic and some other additive components like rheology and surface tension modifiers, humectants, binders and defoamers, that provide a better performance of the overall system.<sup>1,20,23</sup> The conductive material may be in the form of dispersed nanoparticles (NPs), a dissolved organometallic compound, or a conductive polymer that can be dissolved or dispersed.<sup>1,13,23</sup> The choice of material depends on the required physical properties of what is going to be printed, such as conductivity, optical transparency, stability to bending, adhesion to the substrate, physicochemical properties of the resulting ink (like aggregation) and finally compatibility to the printer itself.<sup>1</sup>

The developed ink should have good printability, high resolution, enable minimum printer maintenance and a long shelf life, which means properties like surface tension, viscosity, wettability and adhesion to the substrate should be controlled to achieve an optimal print.<sup>1,13,18,25</sup>

Nowadays the most used material is metal NPs and the wet chemical methods used today to produce those NPs are able to meet the large scale requirements for inkjet ink formulation.<sup>1</sup> These NPs are suspended in water or an organic solvent, such as toluene or ethylene glycol.<sup>1</sup> The solvent chosen must quickly evaporate when deposited but not so fast that dries out at the nozzle leading to a series of problems as clogging.<sup>23</sup> For example, silver (Ag) based metal NPs inks, which is the selected ink for this work, are the most widely used due to its high electrical conductivity and low oxidation<sup>1,5,7,8,13,18,20,25</sup> but due to its high cost (like gold as well)<sup>5</sup> research has been performed to find alternative material like copper or aluminium. These alternative materials are not ideal due to rapid oxidation in ambient condition, leading to an increase in the complexity of the production process in order to control the atmosphere.<sup>1,5,7,13,20,23,25</sup>

These NPs can only be used in inks if they are produced in a way that prevents them from aggregation and precipitation to ensure reproducible performance, so the addition of a stabilizing agent, like a polymeric material or a surfactant, is paramount. These stabilizers are especially important for dispersions with high metal loading (20-60 wt%) which are required to obtain printed patterns with high conductivity.<sup>1</sup> Also, to guaranty a good printability, the NP synthesis has to be done in a way to control the size, shape and distribution of the NPs.<sup>1,13,20,23</sup> As a general good rule of thumb the particle size should be 100 times smaller than the nozzle.<sup>20,23</sup> Another problem with using NPs is the need for a post-printing treatment to remove this stabilizing agents and allowing the NPs to coalesce together in a sintering process (see section 1.3) resulting in conductive patterns.<sup>1,5,13,23</sup>

Is also possible to produce inks based on metal precursors dissolved in solution in the form of ions,<sup>5,13</sup> that in this case would be silver or other metal depending on the needs of the application.<sup>5,13</sup> Since these ions can be prevented from coagulation, the final ink can be very stable over a long time, preventing in this way the clogging of the printing nozzle.<sup>5,23</sup> The downside of this type of ink is the low metal content, which causes an increase of the electrical resistivity and also the complex post-treatment necessary to reduce the ions to elemental silver.<sup>5,23</sup>

Another family of materials to consider for ink fabrication are carbon-based nanomaterials, like carbon nanotubes (CNTs) and graphene<sup>20</sup>, which are very promising in flexible electronics due to their unique properties, such as high intrinsic current mobility and conductivity with a high optical transparency, mechanical flexibility and potential for low-cost fabrication.<sup>1,20</sup> In the case of CNTs their high aspect ratio and van der Waals forces cause them to bundle together and if they become large enough they would cause clogging of the printing nozzle and also would increase the viscosity of the ink, beyond the limits for inkjet printing, leaving the ink unusable or at least with a worst performance compared to other inks.<sup>1,20</sup>

### 1.3 Sintering

To obtain conductive structures the printing pattern must be subjected to sintering. It is in this step that surfactant, present around the NPs in solution will be removed. Making the NPs coalesce to form a continuous electrical path as Figure 1.3 shows.<sup>1,4,5,8,18,19,23</sup>

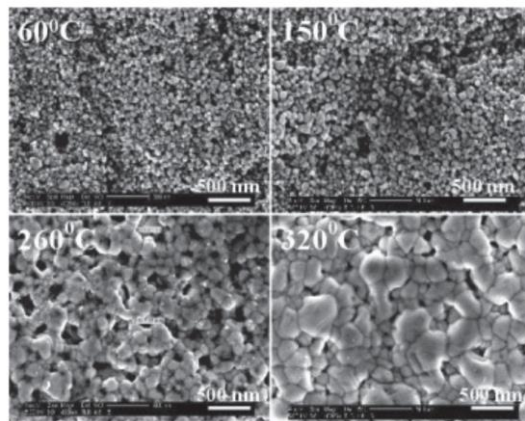


Figure 1.3-SEM images obtained with silver ink deposited on glass and sintered at different temperatures<sup>1</sup>

The most common method is heating the pattern on a hot plate or oven at elevated temperatures, so-called thermal sintering. For silver and copper this happens, around 200-350 °C for 10-60 min, with the printed films achieving resistivity values comparable to that of bulk silver ( $1.6 \times 10^{-8} \Omega\text{m}$ )<sup>18</sup> and copper.<sup>1,5,13,17,23</sup> A problem with this is that most patterns are printed on plastic, paper or on some other kind of heat sensitive substrate which cannot handle such temperatures without damage and can lead to oxidation which reduces the conductivity. For the reasons mentioned above, other alternatives have been studied for sintering.<sup>1,4,5,8,19,23</sup>

Another well-known method is called photonic sintering, which consists on using electromagnetic radiation to sinter the printed patterns. The most common types of radiation used goes from the IR all the way to the UV part of the spectrum, in this case for silver NP ink the most effective is IR<sup>5</sup> resulting in a resistivity 4 times higher than the bulk value.<sup>1</sup> If the substrate is not sensitive to this kind of radiations, this method solves the problem of the high temperatures, because the energy introduced by the electromagnetic radiation is absorbed by the ink and gets confined to the NPs, having little to no effect on the substrate due to its transparency to the radiation if selected properly.<sup>1,4,5,17,23</sup>

The fact that the principle of photonic sintering is the absorption of a specific wavelength of radiation it becomes possible to make use of lasers to take this concept to the next level. By narrowing the wavelength window or even selecting a single wavelength to match the absorption spectrum of the selected ink, maximizing the efficiency of this sintering process.<sup>1,4,23</sup> Photonic sintering is an ultra-fast process, it can be done in single or multiple flashes of radiation and is compatible with industrial processes, turning it into an attractive alternative over conventional thermal sintering.<sup>1,4,17,23</sup>

Another way to make the printed patterns conductive, in a reduced amount of time and without destroying the substrate is using a microwave oven to submit the pattern to microwave radiation<sup>5,23</sup>, which the metals are able to absorb but they have a very small penetration depth, just around of 1-2  $\mu\text{m}$  for silver, gold and copper at a frequency of 2.54 GHz.<sup>1,19,23</sup> This means that in order for this technique to be successful the thickness of the printed patterns has to be in the same range of the penetration depth.<sup>1,19,23</sup> In the case of most metals, is possible to extend pass that limit due to the fact that they are good thermal conductors.<sup>1</sup>

Finally, other less used methods of sintering are electrical sintering, which uses Joules-effects heating to sinter the film.<sup>23</sup> It's done by applying a potential difference across the printed pattern creating a current which will generate a localized heating of the ink. An important thing with this method is that the pattern has to be already slightly conductive before sintering.<sup>1,23</sup> It is also possible to use plasma sintering which is done normally by exposing the printed pattern to low-pressure argon plasma and the last one is chemical sintering which promotes the coalescence of metal NP through the use of chemical reactions that can be done at room temperature.<sup>1,5,6</sup>



## 2. Methodology

This section, describes the different materials and methodologies used to achieve the final prototype, which will have a similar structure to the Figure 2.1 (not at scale), with two printed metal layers separated by a printed electrically insulating material, with vias through the insulator at specific places where the two conductive layers need to be connected to assure circuit functionality. For the final prototype, this metallization scheme is printed on top of a glass substrate with discrete oxide TFTs.

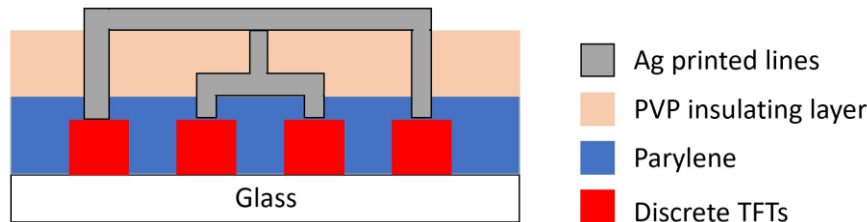


Figure 2.1-Schematic of a cross-section of the final prototype, comprising a printed, multilevel metallization scheme on a glass substrate with discrete oxide TFTs.

### 2.1 Conductive layer

To fabricate the conductive layer the material chosen was a commercially available Ag ink by Sicrys. This specific product (Sicrys 150T-13) has a 50% metal loading of silver nanoparticles with a d50 value of 70 nm and a viscosity of 26 cP.

To carry out the printing of the conductive ink, it was used a Pixdro LP50 printer equipped with an assembly module compatible with Fujifilm Dimatix heads, specifically the 11610 model with 16 nozzles, spaced 254  $\mu\text{m}$ , each with a diameter of 21  $\mu\text{m}$  and a calibrated drop size of 10 pL.

The printer is controlled by a software with a vector image as an input from a graphic illustration program like Inkscape, which converts the black and white pattern to a printable data.

To optimize the printing process towards the lowest possible electrical resistivity and highest lateral resolution a pattern was designed (Figure 2.2) using Inkscape, consisting of two lines with width of 100 and 50  $\mu\text{m}$  and 1 cm between the two pads (squares of  $500 \times 500 \mu\text{m}^2$ ).

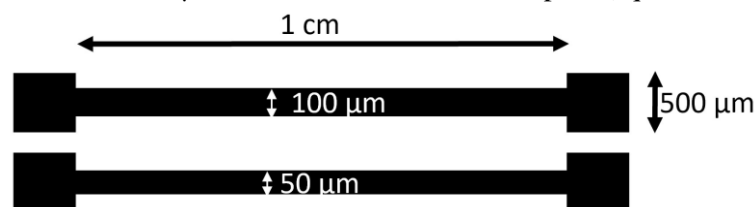


Figure 2.2- Inkscape pattern of conductive lines for optimization of the Ag printing process

Next, the pattern was printed under a combination of several conditions summarized in Table 2.1, over soda-lime glass cleaned with acetone and isopropanol and dried with nitrogen gas.

Table 2.1- Summary of the different printing variables tested to achieve conductive Ag lines

Substrate temperature (°C)	Speed (mm/s)	Drops per inch (DPI)
30	1	750
50	10	1000
70	50	1500
-	100	2000
-	150	3000

For the calibration of the jetting process, the nozzles were heated to 31 °C, but during printing, only one active nozzle was used. To ensure the best droplet formation a set of 3 voltages in a custom waveform were applied to the piezoelectric crystal, those were 3, 5 and 25 V, respectively.

To make the silver lines conductive, a post-printing annealing is required, so the best printing condition is selected to make sure that the only thing affecting the conductivity of the lines is the annealing process.

First, a conventional thermal process on a hot plate was performed, utilizing different temperatures (180, 200, 250 and 300 °C) over a period of 15, 30 and 60 minutes and their electrical resistance was measured.

Next, a combination of thermal and photonic annealing was tested, with a hot plate set at 180 °C and an IR lamp (Philips BR125, with 250 W and a maximum radiation peak at a wavelength of 1100 nm) at 1 cm away from the sample, over a period of 5, 10, 15 and 30 minutes and the resistance was measured as well.

The printing on the insulating layer was done by a multi-layer approach, where the speed was kept constant at 50 mm/s and changing the DPI from 300 to 500 and the number of layers from 1 to 4. Finally, the post-treatment applied was a simple thermal annealing of 180 °C for 30 min over a hot plate.

## 2.2 Insulating layer

For the insulating layer a solution of polyvinylpyrrolidone (PVP) from Sigma-Aldrich (CAS: 9003-39-8) with an average molecular weight of 10000, was prepared by mixing 2 g of PVP in 10 mL of ethanol and stirred for 4 hours.

To deposit the PVP solution a shear casting system (K101 control coated system) was used. The system utilizes a heated bed with a temperature control that was set to ambient temperature and 30 °C. The speed of the deposition was also evaluated (1 and 2 mm/s), as well as the number of layers (1 and 2 layers) and direction of coating, to see which condition gives the best thickness and uniformity.

To make sure that the solvent was evaporated and the PVP has hardened, the films were baked in a hot plate at 180 °C for 30 min.

## 2.3 Via formation by laser ablation

To create vias through the insulating layer a Universal Laser System CO<sub>2</sub> VLS 3.5 operating in the infrared region of 10.6 μm was employed. Plano-convex lens of type 2.0" with focal length of 50.8 mm, focus point of 0.127 mm and depth of focus of 2.54 mm were utilized to focus the laser beam and keep the performance constant for all the tests.

The laser system was controlled using a vector image input from Adobe Illustrator, defined in the form of red, green and blue (RGB) colour map. Raster mode was selected to work at the surface of the material, meanwhile, nitrogen gas was used to cool down the sample during the process. To remove the PVP solution the speed of the laser was kept at 1 % and only the power and the pulses per inch (PPI) were changed from 1 to 3 % and from 1000 to 800 respectively.

## 2.4 Characterization methods (morphological and electrical analysis)

All the silver lines were observed under an optical microscope (Olympus BX51) and their width and thickness were measured using Image J software and profilometer (Ambios XP-200 plus) equipped with a diamond stylus tip, respectively. The electrical measurements to extract the I-V curves were carried out using a semiconductor parameter analyser (Agilent 4155C) and a microprobe station (Cascade M150) at room temperature and in the dark. IV-curves were taken for conductive lines in a single layer, for conductive lines containing the two metal layers (through a via in PVP), as well as for the metal-insulator-metal stack to access the breakdown field of the insulating material.

The thickness and uniformity of the PVP films were measured by the same profilometer mentioned above.

To optimize the laser ablation process on PVP vias were examined by a benchtop scanning electron microscope equipped with an energy dispersive detector (SEM-EDS, Hitachi TM



3030plus Tabletop), as well as by the electrical measurements of conductive lines for the two metal lines contacted through a PVP via, as previously mentioned.

## 2.5 Final prototype

After the oxide TFTs were produced and passivated in clean room environment, the digital circuit blocks are selected and the metallization patterns are designed to be printed following these steps: i) the first metal layer is printed with a resolution of 400 DPI, a speed of 50 mm/s with three printing layers; ii) This layer is annealed at 200 °C for 30 min and other sample is sintered for 5 min under an IR lamp for comparative effects; iii) The PVP solution is deposited with two layers (with the second layer being deposited in the opposite direction with respect to the first layer) at a 1 mm/s speed, with the substrate temperature of 30 °C and finally cured at 180 °C for 30 min; iv) The second metallization layer is printed and annealed exactly as the first one.

The circuits are characterized in the DC domain using the same semiconductor analyser and the probe station described in 2.4.



### 3. Results and discussion

#### 3.1 Printing process

##### 3.1.1 Inkjet printing silver lines on glass substrate

This section discusses the effects of different variables on the printing process. To narrow down the most useful values for those variables a quick and general study of all the parameters was performed.

The first parameter studied was the resolution measured in drops per inch (DPI), keeping the speed constantly at 150 mm/s and no substrate heating. The results, in terms of the linewidth, can be observed in the table below.

Table 3.1- Results of the effect of the DPIs in the morphology of the printed Ag lines.

DPI	Line 100 $\mu\text{m}$		Line 50 $\mu\text{m}$	
	Average width ( $\mu\text{m}$ )	Standard Deviation	Average width ( $\mu\text{m}$ )	Standard Deviation
750	91.85	8.47	55.48	3.38
1000	118.61	12.01	76.00	13.49
1500	142.23	24.24	85.50	10.92
2000	156.03	33.06	88.10	22.52
3000	219.38	68.90	107.09	20.14

From the Table 3.1 it is easy to conclude that the 750 DPI is the best for both set of lines, but as the figure below shows both 50 (Figure 3.1a)) and 100  $\mu\text{m}$  (Figure 3.1d)) lines are not continuous which is not useful for the final objective of achieving transistors interconnections.

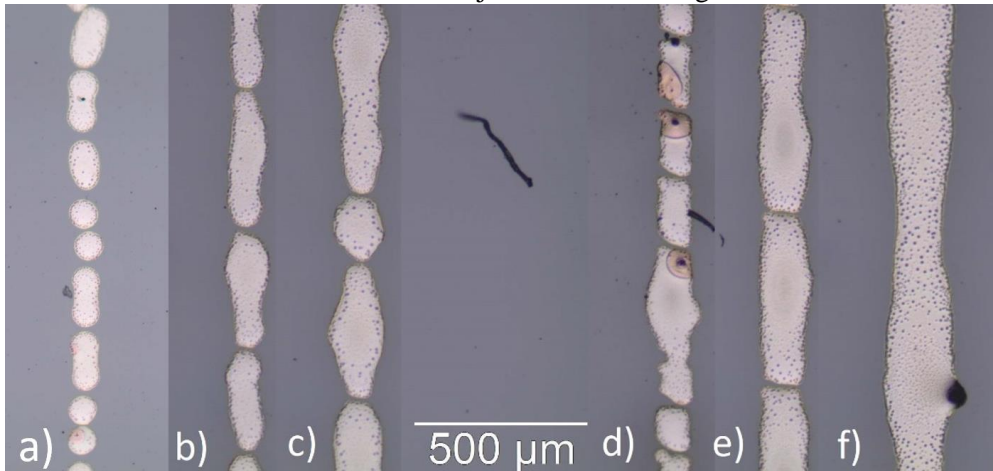


Figure 3.1-Effect of the resolution in the morphology of the printed Ag lines; a) to c) 50  $\mu\text{m}$  lines with 750, 1000 and 1500 DPI respectively; d) to f) 100  $\mu\text{m}$  lines with 750, 1000 and 1500 DPI respectively.

To solve that the best way would be to increase the DPI and from the Figure 3.1b) and e) it is possible to observe that the gaps between the droplets are smaller, so if the DPIs are increased to 1500 the set of 100  $\mu\text{m}$  lines (Figure 3.1f)) are now continuous due to being deposited more ink. However, for the set of 50  $\mu\text{m}$  lines (Figure 3.1c)) it is still a problem, which means that there are other variables that need to be considered, like the printing speed and the substrate temperature. Another problem with 1500 DPIs is that significant bulges start appearing and from the Table 3.1 it is possible to see an increase in the average width and standard deviation, so probably the best values to be used in the future would be 750 and 1000 DPIs.

The next parameter studied was the speed of the printing plate measured in mm/s. For this end, DPI was set to 1000 and the temperature of the substrate at around 22 °C (laboratory temperature). The table below shows the results of the different speed values tested.

Table 3.2- Results of the effect of the printing speed in the morphology of the printed Ag lines.

Speed (mm/s)	Line 100 $\mu\text{m}$		Line 50 $\mu\text{m}$	
	Average width ( $\mu\text{m}$ )	Standard Deviation	Average width ( $\mu\text{m}$ )	Standard Deviation
<b>100</b>	108.25	4.97	73.55	7.69
<b>50</b>	128.22	16.50	100.40	39.26
<b>10</b>	129.17	11.87	88.25	21.97
<b>1</b>	139.46	13.38	92.69	26.98

These results shows that the 100 mm/s speed is the best for both lines, but as the Figure 3.2a) and Figure 3.2d) demonstrate the problem of discontinuities in the lines it is still present, like in the previous test. Slowing down the speed solves this problem but this creates even bigger bulges, which is confirmed by the increase in the standard deviation as well in Figure 3.2b), c) and e).

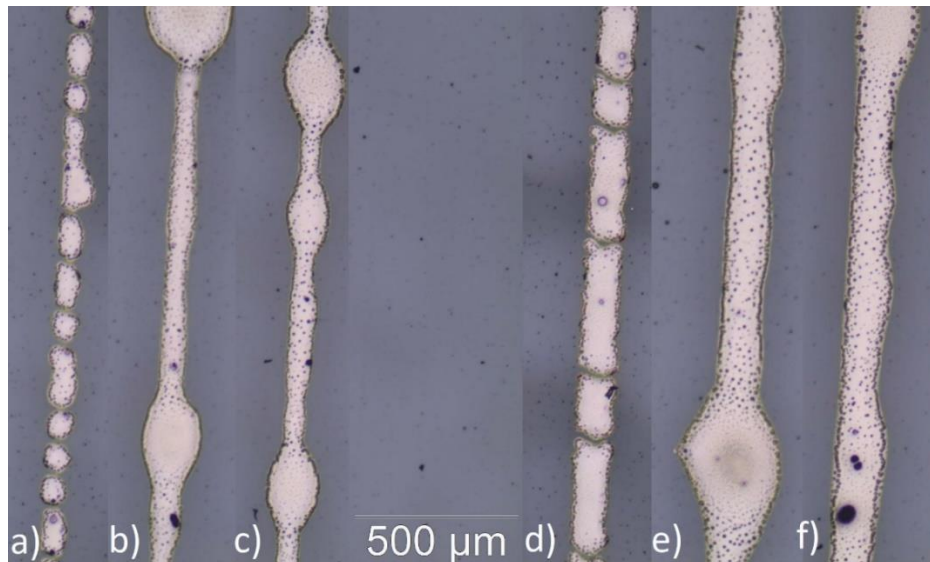


Figure 3.2- Effect of the printing speed in the morphology of the printed Ag lines a) to c) 50  $\mu\text{m}$  lines with a printing speed of 100, 50 and 10 mm/s respectively; d) to f) 100  $\mu\text{m}$  lines with a printing speed of 100, 50 and 10 mm/s respectively.

Another observation from Table 3.2 is that for the 100  $\mu\text{m}$  line both 50 and 10 mm/s originated the same results, eliminating the 10 mm/s setting because does not constitute an advantage using a lower speed. Meanwhile, the 1 mm/s speed is the worst of all the conditions tested. In the case of the 50  $\mu\text{m}$  line, the results are inconclusive due to a high DPI value.

These results show that the higher the speed the bigger the resolution to achieve the same printing results. For that reason, different combinations between 100 and 50 mm/s speed and 750 and 1000 DPI resolution will be analysed further.

Finally, the substrate temperature was tested, keeping the speed set at 100 mm/s and resolution at 1000 DPIs. The results are summarized in the table below.

Table 3.3- Results of the effect of the substrate temperature in the morphology of the printed Ag lines.

Substrate temperature (°C)	Line 100 $\mu\text{m}$		Line 50 $\mu\text{m}$	
	Average width ( $\mu\text{m}$ )	Standard Deviation	Average width ( $\mu\text{m}$ )	Standard Deviation
30	106.60	3.31	72.33	4.04
50	105.75	6.97	67.09	4.31
70	115.79	10.35	80.19	10.11

An increase in the substrate temperature improves the uniformity of the printed lines, represented by a significant decrease in the standard deviation (Table 3.3). A problem is when setting the substrate to 70 °C causes an increase in the nozzle temperature, which in turn causes printing instabilities and errors. By leaving the physical properties of the ink outside the expected ranges of the inkjet printing, for those reasons 70 °C it will not be used.

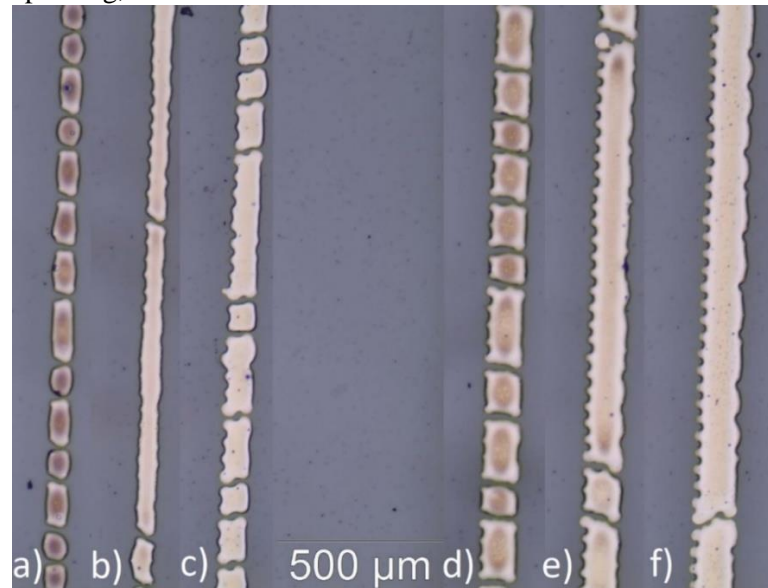


Figure 3.3- Effect of the substrate temperature in the morphology of the printed Ag lines a) to c) 50  $\mu\text{m}$  lines with a substrate temperature of 30, 50 and 70 °C respectively; d) to f) 100  $\mu\text{m}$  lines with a substrate temperature of 30, 50 and 70 °C respectively

From Figure 3.3 b) and Figure 3.3 e) it is possible to observe that the substrate temperature helps in solving the broken lines problem. This is justified by the temperature allowing the droplets to merge together. Nevertheless since 30 and 50 °C are so similar, in terms of line width, both will be tested in the next phase.

In conclusion, in the next phase of testing the best parameters for each variable (attachment B) were combined, only one layer of ink printed and the effects, on the electrical resistivity quantified. To turn the Ag lines electrically conductive it is necessary to apply a sintering process, for example setting a hot plate at 180 °C for 30 min, which is recommended by the ink supplier. To simplify the understanding of the results, the 100  $\mu\text{m}$  lines are the first to be studied. The printing conditions are substrate temperature set at 30 °C, while speed and DPI vary, for each condition the resistance and the geometrical parameters (width and thickness) were measured and summarized in Table 3.4.

Table 3.4-Electrical resistivity for the 100  $\mu\text{m}$  line with the substrate temperature of 30  $^{\circ}\text{C}$  with different speeds and DPIs

Condition		Width ( $\mu\text{m}$ )		Thickness (nm)		Resistance ( $\Omega$ )	Resistivity ( $\Omega\text{m}$ )
Speed (mm/s)	DPI	Average	Standard deviation	Average	Standard deviation		
100	750	120.53	6.53	954.22	203.85	110.60	$1.27 \times 10^{-6}$
	1000	111.70	7.86	935.67	126.79	$>10^9$	$>10$
50	750	113.83	9.31	941.56	126.76	41.17	$4.41 \times 10^{-7}$
	1000	113.13	10.29	1153.22	169.51	20.34	$2.65 \times 10^{-7}$

One result to highlight it is the second printing condition (speed of 100 mm/s and 1000 DPI) that has an electrical resistance greater than  $10^9 \Omega$ , this mean that the line was not conductive and the reason is represented in Figure 3.4b), which shows that the line is interrupted preventing the flow of current.

The last condition (speed of 50 mm/s and 1000 DPI) is the best one by having the lowest electrical resistivity. This can be justified by the fact that the line has the biggest cross-sectional area, due to an increase in thickness, caused by an increase in the amount of ink being deposited.

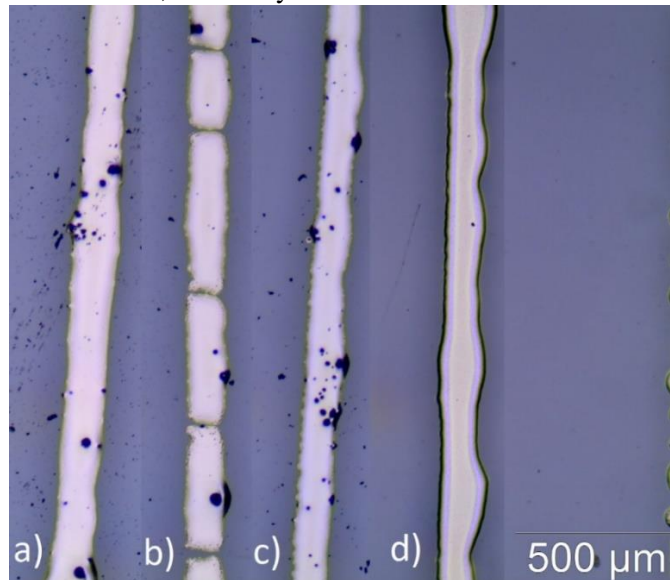


Figure 3.4- 100  $\mu\text{m}$  Ag line printed with a substrate temperature of 30  $^{\circ}\text{C}$ ; a) speed of 100 mm/s and 750 DPI; b) speed of 100 mm/s and 1000 DPI; c) speed of 50 mm/s and 750 DPI; d) speed of 50 mm/s and 1000 DPI

This increase in ink is useful for lowering the electrical resistivity but can cause deformations, like bulges, in the line as it can be observed in Figure 3.4d). So, an optimization must be achieved between the electrical properties and morphology of the line. In this context the best condition is the one with 50 mm/s speed and 750 DPI (Figure 3.4c)).

Figure 3.4 also shows some blue dots, this is unseen impurities at the time of printing and sintering, but they didn't influence the results because different parallel samples obtained the same results without impurities.

By changing the substrate temperature to 50  $^{\circ}\text{C}$  it was possible to obtain consistent electrical performances across different printing conditions, as Table 3.5 confirms. This is due to an, expected, increase in thickness because as the droplets encounter a hotter substrate, this promotes a faster evaporation of the solvent, which leads to a faster solidification of those droplets instead of spreading. Another effect is the increase in lateral resolution of the printed lines, as expected, by allowing the printed lines to have a smaller width closer to the printing pattern.

Table 3.5- Electrical resistivity for the 100 μm line with the substrate temperature of 50 °C with different speeds and DPIs

Condition		Width (μm)		Thickness (μm)		Resistance (Ω)	Resistivity (Ωm)
Speed (mm/s)	DPI	Average	Standard deviation	Average	Standard deviation		
100	750	102.15	7.93	1.01	0.34	>10 <sup>9</sup>	>10
	1000	122.34	18.24	1.43	0.40	18.50	3.24 × 10 <sup>-7</sup>
50	750	106.89	14.86	1.02	0.17	31.06	3.41 × 10 <sup>-7</sup>
	1000	128.96	11.44	1.41	0.18	15.56	2.83 × 10 <sup>-7</sup>

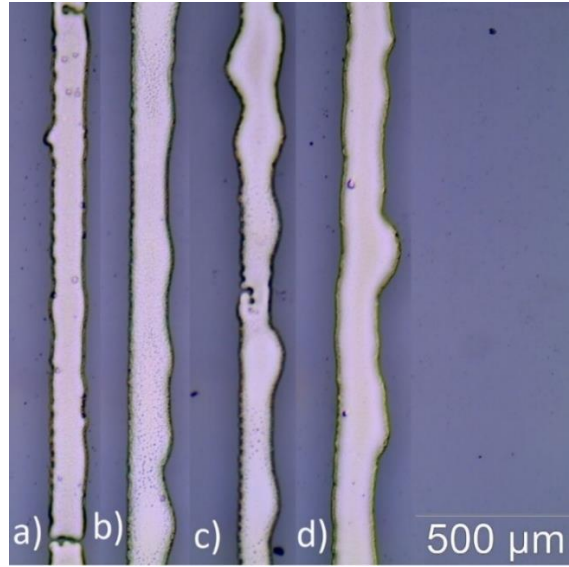


Figure 3.5- 100 μm Ag line printed with a substrate temperature of 50 °C; a) speed of 100 mm/s and 750 DPI; b) speed of 100 mm/s and 1000 DPI; c) speed of 50 mm/s and 750 DPI; d) speed of 50 mm/s and 1000 DPI

When analysing Figure 3.5c) it is possible to see deformations that previously did not exist, as an increase in the standard deviation also confirms. This is due to a high humidity content (superior to 50 %) in the air or due to instabilities of the printing nozzle, caused by wear of the piezoelectric crystal. The effect of all this are changes to the jetting and droplet formation causing instabilities on the falling droplets, as Figure 3.6 shows.

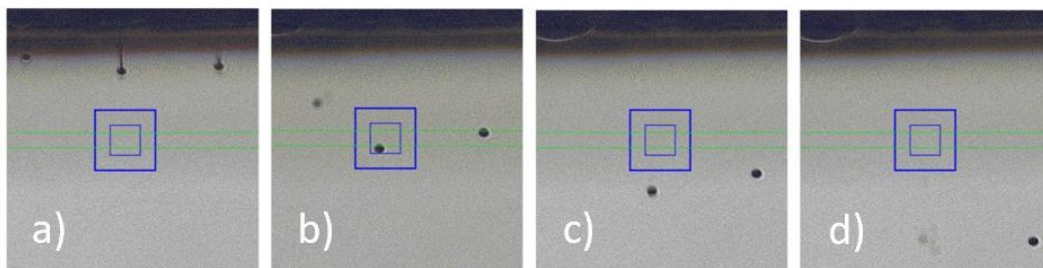


Figure 3.6- Time-lapse of the droplet formation under 50 % humidity environment

As the droplets form and fall, they start getting affected by the ambient conditions and if not controlled the effect can be so dramatic that the droplet breaks and disappears like what happens when going from Figure 3.6c) to Figure 3.6d), which causes unpredictability in the printing processes.

To reduce or even sometimes cancel this effect it is possible to change the voltage values that control the piezoelectric response of the crystal responsible for producing the droplets. However, as attachment C shows, this is not the optimal solutions because the droplet tail can

cause another set of problems like unwanted amounts of ink or little satellite droplets in the substrate.<sup>22</sup>

In summary, despite the jetting problems, for the 100 μm lines the best printing conditions are setting the substrate temperature to 50 °C and print with 50 mm/s speed and 750 DPI because it has the smallest width while maintaining a good electrical performance.

Since the inkjet process is very sensitive to changes, from the design of the pattern to the environment conditions in the lab, it is necessary to confirm that changing the width from 100 to 50 μm the conclusions already discussed, stay the same. For that reason, the exact same parameters and conditions were re-tested for this new linewidth. The electrical and geometrical results are summarized in Table 3.6, Table 3.7, Figure 3.7 and Figure 3.8.

Table 3.6- Electrical resistivity for the 50 μm line with the substrate temperature of 30 °C with different speeds and DPIs

Condition		Width (μm)		Thickness (μm)		Resistance (Ω)	Resistivity (Ωm)
Speed (mm/s)	DPI	Average	Standard deviation	Average	Standard deviation		
100	750	68.49	9.93	Not measured		>10 <sup>9</sup>	>10
	1000	70.27	7.36	Not measured		>10 <sup>9</sup>	>10
50	750	64.98	13.57	Not measured		>10 <sup>9</sup>	>10
	1000	77.35	14.19	1.11	0.14	39.39	3.38 × 10 <sup>-7</sup>

The first three conditions have an electrical resistance bigger than the equipment limit, the printed lines are considered not to be electrically conductive, for that reason the thickness was not measured.

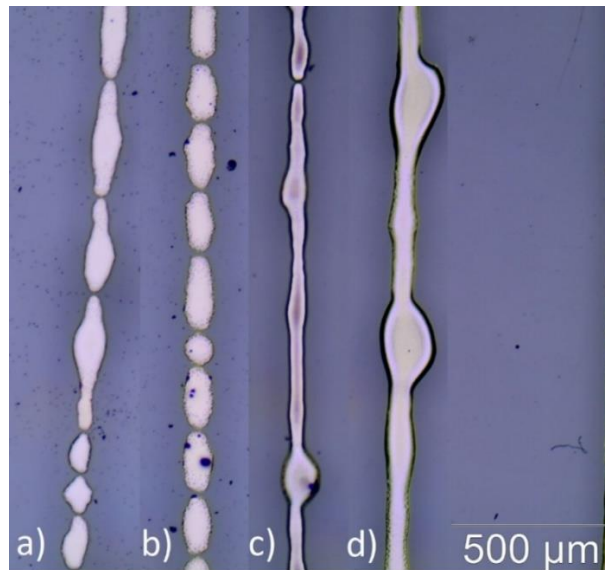


Figure 3.7- 50 μm line printed with a substrate temperature of 30 °C; a) speed of 100 mm/s and 750 DPI; b) speed of 100 mm/s and 1000 DPI; c) speed of 50 mm/s and 750 DPI; d) speed of 50 mm/s and 1000 DPI



Table 3.7- Electrical resistivity for the 50  $\mu\text{m}$  line with the substrate temperature of 50  $^{\circ}\text{C}$  with different speeds and DPIs

Condition		Width ( $\mu\text{m}$ )		Thickness ( $\mu\text{m}$ )		Resistance ( $\Omega$ )	Resistivity ( $\Omega\text{m}$ )
Speed (mm/s)	DPI	Average	Standard deviation	Average	Standard deviation		
100	750	55.85	13.87	Not measured		$>10^9$	$>10$
100	1000	71.12	10.15	1.13	0.32	31.96	$2.57 \times 10^{-7}$
50	750	66.50	12.57	0.62	0.18	143.55	$5.96 \times 10^{-7}$
50	1000	65.39	8.52	1.02	0.12	38.15	$2.54 \times 10^{-7}$

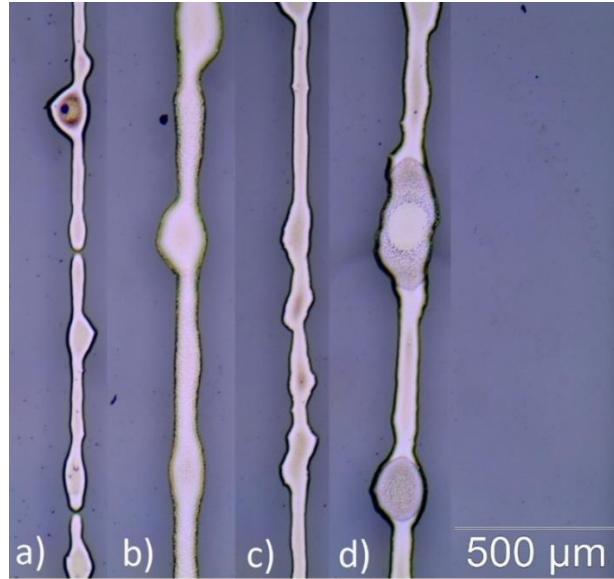


Figure 3.8- 50  $\mu\text{m}$  line printed with a substrate temperature of 50  $^{\circ}\text{C}$ ; a) speed of 100 mm/s and 750 DPI; b) speed of 100 mm/s and 1000 DPI; c) speed of 50 mm/s and 750 DPI; d) speed of 50 mm/s and 1000 DPI

For the case of 50  $\mu\text{m}$  lines the exact same conclusions as the 100  $\mu\text{m}$  can be observed and confirms that changing the printing pattern doesn't have a significant effect on the performance of the Ag lines. Since the same printing conditions is able to print lines with a balance between cross-sectional area and electrical performance for both set of lines, the overall process can be simplified because it is possible to change the width of the lines depending on the performance needed without changing printing conditions.

### 3.1.2 Deposition of PVP

The deposition of the PVP solution accomplished with shear casting was studied with the objective of obtaining a uniform layer with a minimum thickness of 1  $\mu\text{m}$  to guaranty the insulation between multiple conductive layers. Figure 3.9 represents the profile obtained when different shear casting speeds (1 mm/s and 2 mm/s) were applied.

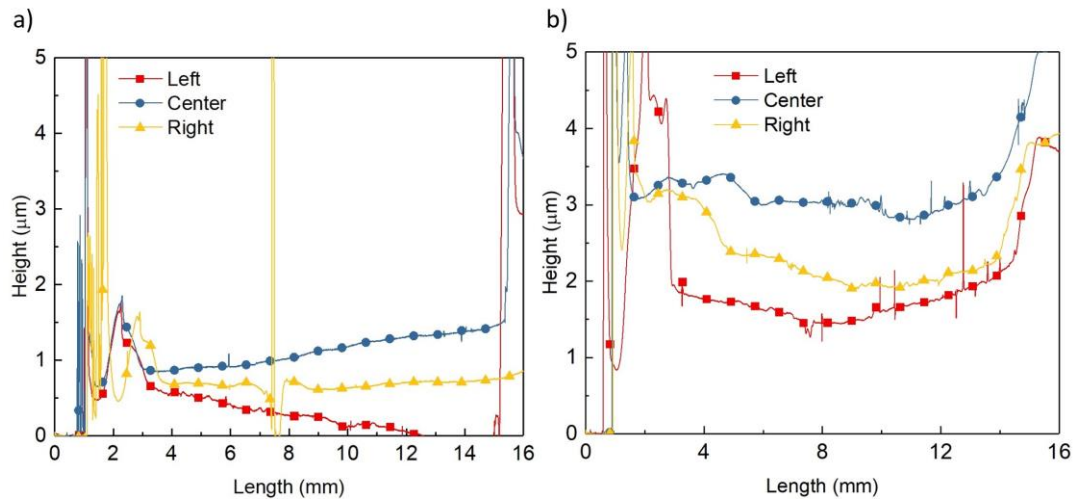


Figure 3.9- Profile taken at three different points of the insulating PVP layer obtained with two different shear casting speeds; a) 1 mm/s; b) 2 mm/s

From the figure above it is possible to observe that 2 mm/s speed (Figure 3.9b)) deposits a film with the required thickness but it is not uniform or consistent. This effect is due to a low viscosity of the insulating PVP solution, causing a worst control over the deposition process. In the case of 1 mm/s speed (Figure 3.9a)) the thickness is lower than required, making it unusable.

To solve this samples with two layers were deposited and the results are represented in Figure 3.10.

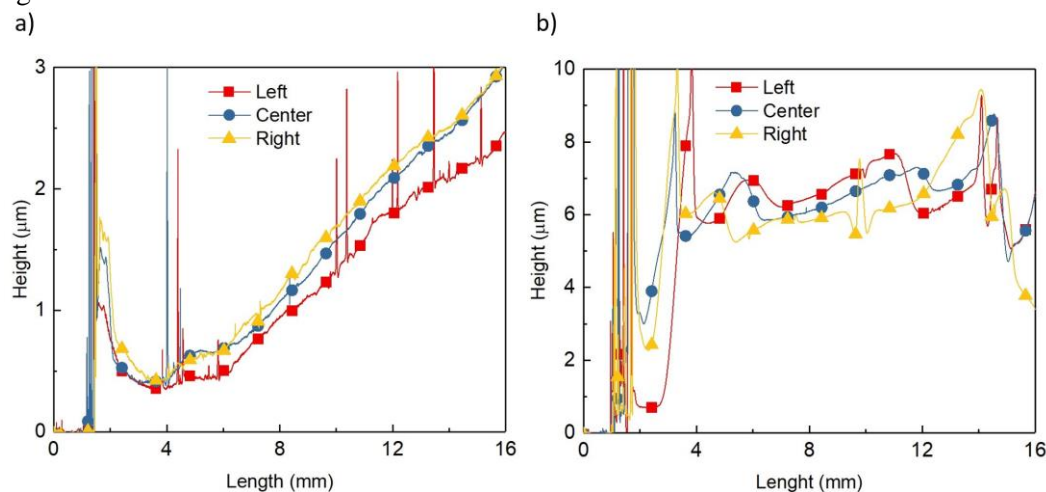


Figure 3.10- Profile taken at three different points of the insulating PVP layer obtained with two different shear casting speeds and printed twice; a) 1 mm/s speed; b) 2 mm/s speed

From the profile, it is possible to observe that the difference in thickness across the samples from left to right is minimal but across the length it is still a problem. In the first sample (Figure 3.10a)) the ascending profile prevents this condition to be useful by complicating the laser etching process, explained in section 3.4. However in the 2 mm/s sample (Figure 3.10b)) the thickness is unnecessarily thick and the profile exhibits more scattering than the 1 mm/s sample, which could present a problem to effectively print the second conductive layer.

Since the PVP solution is alcohol-based, introducing temperature to the process allows a faster hardening of the PVP, by helping with solvent evaporation and wettability. This together with depositing the second layer in the opposite direction with respect to the first layer will allow to reduce the ascending profile observed while keeping the uniformity of the profile across the sample, as Figure 3.11 shows.

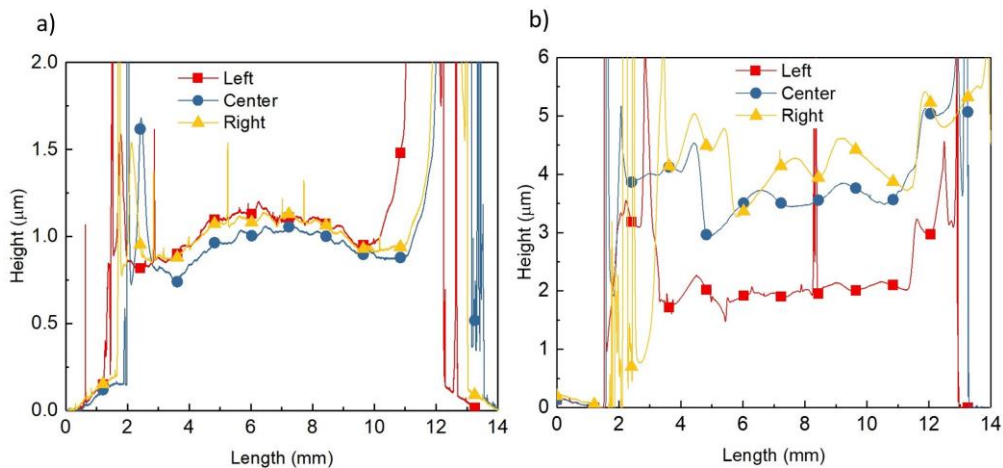


Figure 3.11- Profile taken at three different points of the insulating PVP layer deposited twice, with the second layer deposited in the opposite direction with respect to the first one and with two different shear casting speeds at 30 °C; a) 1 mm/s speed; b) 2 mm/s speed

From the profile of Figure 3.11b) it was not possible to keep the uniformity of the insulating layer, as desired for consistent and reproducible performance, because the deposition occurs too fast (coupled with the small variations introduced by the equipment) for allowing the deposition to occur predictability. Even though the thickness is sufficient for the desired application that problem with the uniformity of the profile, turns it unfit for the final application. Meanwhile in Figure 3.11a) is possible to observe the desired uniform profile, even with few defects, but less thickness than required, so the solution found was to add more PVP solution.

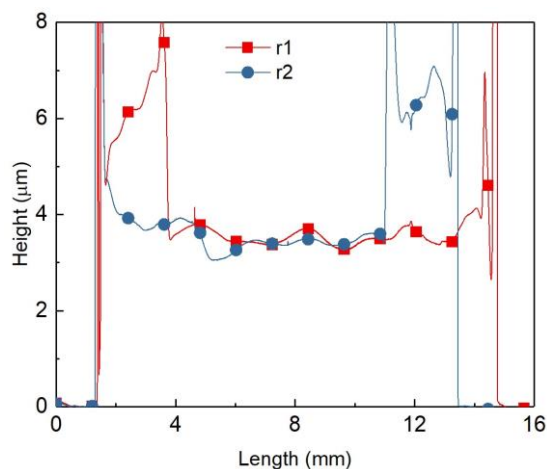


Figure 3.12- Profile of two parallel samples of insulating PVP layer deposited twice, with the second layer deposited in the opposite direction with respect to the first one, at 1 mm/s shear casting speed and 30 °C.

From Figure 3.12 it is possible to observe that adding a larger volume of PVP solution solved the problem of insufficient thickness. The two parallel samples (r1 and r2) have the same profile and average thickness across the entire sample. Since the objective was to have a minimum thickness of 1 µm, with these conditions it was possible to have a thickness of 4 µm, which is enough to prevent short circuits between the two conductive layers.

### 3.1.3 Inkjet printing silver lines on PVP substrate

After depositing the insulating layer, a new conductive layer is printed but now on top of PVP, which naturally has different surface properties compared to glass, like surface energy, contact angle and wettability. Which means that the previous printing conditions would not achieve the same results as in section 3.1.1, as Figure 3.13 and Table 3.8 shows.

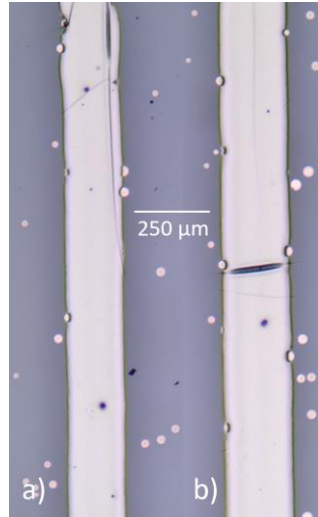


Figure 3.13- Ag lines printed on PVP with substrate temperature of 50 °C, speed of 50 mm/s and 750 DPI a) 50 μm line b) 100 μm line.

Table 3.8- Width of Ag lines printed on PVP with substrate temperature of 50 °C, speed of 50 mm/s and 750 DPI.

Line	Width (μm)	
	Average	Standard deviation
100 μm	229.28	3.62
50 μm	186.11	5.31

Using the previous printing conditions causes a dramatic increase in the width of both lines, 114 % for 100 μm and 180 % for 50 μm line. This can be justified by the PVP having better wettability than glass, which is very useful to decrease the line edge roughness of the printed lines. However, the final prototype requires the line width to be the smallest possible, so new printing conditions must be utilized. These new printing conditions are based on decreasing the DPI and adding more printing layers, allowing the printed lines to have enough material to be electrically conductive but without having poor line edge roughness. All lines were printed using substrate temperature of 50 °C and speed of 50 mm/s, changing only the DPI and the number of printed layers. The sintering method was 180 °C for 30 min.

The morphological and electrical performance results for the 100 μm lines are shown in Table 3.9 and Figure 3.14.

Table 3.9- Electrical resistivity for the 100 μm line with different DPIs and number of printed layers.

Condition		Width (μm)		Thickness (nm)		Resistance (Ω)	Resistivity (Ωm)
DPI	Number of layers	Average	Standard deviation	Average	Standard deviation		
300	3	265.11	61.10	300.89	60.73	89.01	$7.10 \times 10^{-7}$
	4	281.24	22.22	334.33	24.14	177.13	$1.67 \times 10^{-6}$
400	2	160.34	6.74	436.78	25.55	$>10^9$	$>10$
	3	202.66	13.08	504.78	44.38	25.70	$2.63 \times 10^{-7}$
500	1	255.51	17.91	153.22	7.64	1403.00	$5.49 \times 10^{-6}$
	2	242.37	23.94	307.00	38.50	648.52	$4.83 \times 10^{-6}$

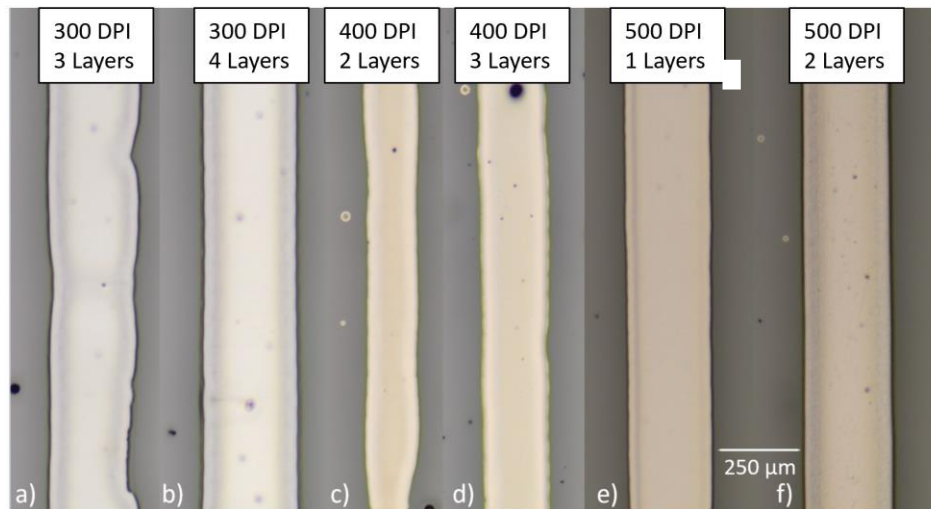


Figure 3.14- 100  $\mu\text{m}$  Ag lines printed on PVP with a substrate temperature of 50  $^{\circ}\text{C}$  and speed of 50 mm/s.

Even with this new printing conditions, the linewidth remains outside the requirements for the final prototype. This problem is solved by reducing the linewidth in the computer software, as it was tested in later stages of this work.

Since the different layers were printed without stopping in between layers, combined with a high substrate temperature and a low volume of ink. This causes a faster evaporation of the solvent, which results in a faster solidification of the droplets of ink preventing the merging of those droplets and subsequently the different layers. This fact explains the unexpected increase in electrical resistivity when comparing the two printing conditions with 300 DPI.

When the DPI increases to 400 and three layers are printed, it is possible to obtain the lowest electrical resistivity ( $2.63 \times 10^{-7} \Omega\text{m}$ ) and when compared to the best electrically performing printed line on glass ( $3.41 \times 10^{-7} \Omega\text{m}$ ), it is possible to obtain comparable electrical resistivities.

Regarding the 50  $\mu\text{m}$  wide lines, they demonstrate the same effects already discussed above for the 100  $\mu\text{m}$  lines, concluding that 400 DPI with three printed layers is the best printing condition, as attachment D and attachment E shows.

In conclusion, the printing on PVP clearly shows one of the major challenges of inkjet printing, which is when changing one parameter of the process the conditions must be re-tested and most of the time new printing conditions have to be introduced. For example, if the dielectric layer has a different material, the surface properties have to be considered and the printing conditions optimized for this new material.

## 3.2 Sintering methods

### 3.2.1 Thermal annealing

This section describes the effects of the annealing temperature coupled with the duration of the annealing process. This study is carried out with a glass substrate and utilizing the best printing conditions found in section 3.1.1 (substrate temperature of 50  $^{\circ}\text{C}$ , 750 DPI and 50 mm/s speed).

The sintering conditions to be studied are four different temperatures (180, 200, 250 and 300  $^{\circ}\text{C}$ ) for three different times (15, 30 and 60 min) on a hot plate, the different resistivities were calculated and represented in Figure 3.15

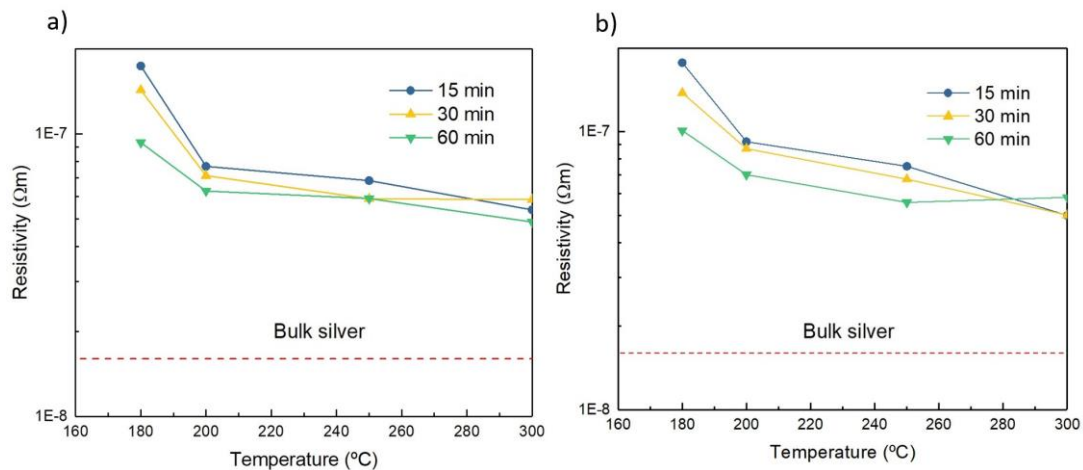


Figure 3.15- Resistivity Vs temperature plot for the different thermal sintering times; a) 100  $\mu\text{m}$  lines b) 50  $\mu\text{m}$  lines.

Analysing Figure 3.15 it is possible to observe a decrease in the electrical resistivity for both lines when the temperature rises. This effect is due to a higher temperature removing the stabilizing agents protecting the NPs in the ink and allowing them to coalesce and form a conductive path and not due to a change in the thickness of the printed lines.

Figure 3.15 also shows the stabilizations of the electrical resistivity, this happens when the NPs no longer are able to coalesce any further, arriving at the limit of electrical performance of this particular ink.

In the case of the 100  $\mu\text{m}$  line (Figure 3.15a) and 15 min on a hot plate there is a 44 % decrease in electrical resistivity at 200  $^{\circ}\text{C}$  when compared to 180  $^{\circ}\text{C}$ . This means that 200  $^{\circ}\text{C}$  gives the best balance between energy spent versus electrical resistivity obtained, which is advantageous when minimizing the production costs by not utilizing high temperatures when possible.

When the sintering time was doubled to 30 min the same effect described above are represented, for this sintering condition the decrease in electrical resistivity at 200  $^{\circ}\text{C}$  was of 50 % comparing to 180  $^{\circ}\text{C}$ . For example, the 100  $\mu\text{m}$  line achieved an electrical resistivity of  $7.12 \times 10^{-8} \Omega\text{m}$ , using 200  $^{\circ}\text{C}$  for 30 min were previously to achieve the same value it was necessary to use 250  $^{\circ}\text{C}$ , which can decrease the fabrication costs and allowing temperature-sensitive applications to be viable. These conclusions are also present in the 50  $\mu\text{m}$  lines to the same degree.

The lowest resistivity obtained at 300  $^{\circ}\text{C}$  ( $5.00 \times 10^{-8} \Omega\text{m}$ ) is 3 times the bulk value for silver of  $1.6 \times 10^{-8} \Omega\text{m}$ . In literature are reported different values for electrical resistivity depending on the type of ink and the sintering conditions used. For example, in the same amount of time is achievable an electric resistivity of  $1.68 \times 10^{-8} \Omega\text{m}$  by using 700  $^{\circ}\text{C}$ <sup>7</sup>. Meanwhile, with a 20 wt% metal loading ink at 650  $^{\circ}\text{C}$  for 60 min, it was only achievable  $2.1 \times 10^{-8} \Omega\text{m}$ <sup>26</sup>. In all the reference found none reported a result lower than the bulk value for silver, because at higher sintering temperatures the silver NPs began to sublimate.<sup>7</sup> However, a minimum temperatures for removing the capping agents, surrounding the NPs has been reported to be 150  $^{\circ}\text{C}$ .<sup>5</sup>

Nevertheless, in order to optimize the sintering conditions a balance between temperature and time must be achieved, for example, by using 200  $^{\circ}\text{C}$  the 100  $\mu\text{m}$  line obtained an electrical resistivity of  $6.28 \times 10^{-8} \Omega\text{m}$  whereas for the same temperature but half the time the electrical resistivity obtained was  $7.12 \times 10^{-8} \Omega\text{m}$ , which translates to 13 % increase. Therefore, the extra amount of time spent is not worth it for an industrial application.

In conclusions, the changes in electrical resistivity comes down to the amount of energy introduced to the system, which means that the same result is achievable by using high temperatures with a small amount of time or vice versa, as it was explained above when comparing with the state of the art. From an application point of view, the sintering condition

should have an equilibrium between temperature and time. For these reasons 200 °C for 30 min, which resulted in a resistivity 4.5 times the bulk value, it is the optimal sintering conditions.

The sintering condition has been optimized and three parallel samples of 100 and 50 μm lines each were printed and tested for reproducibility propose. The resulting I-V curves and electrical resistivities can be observed in attachment F and Table 3.10 respectively.

Table 3.10- Electrical resistivity of the different parallel samples for the selected sintering condition (200 °C for 30 min on a hot plate).

Lines	Resistivity (Ωm)			Average (Ωm)	Standard deviation
	1	2	3		
100 μm	$7.76 \times 10^{-8}$	$7.17 \times 10^{-8}$	$7.13 \times 10^{-8}$	$7.35 \times 10^{-8}$	$2.89 \times 10^{-9}$
50 μm	-	$8.69 \times 10^{-8}$	$1.09 \times 10^{-7}$	$9.78 \times 10^{-8}$	$1.08 \times 10^{-8}$

For the 100 μm lines, there is almost no variation in electrical performance, confirmed by the standard deviation in Table 3.10 as well as the overlapping I-V curves from attachment F. Meanwhile, the 50 μm lines present a little more variation, because printing such small linewidths is more challenging due to the printing parameters, such as droplet size, wettability, ink viscosity and ambient conditions at the time of printing having a bigger influence on the results. Nevertheless, that variations observed in both lines are within statistical acceptance, confirming that exist reproducibility.

### 3.2.2 IR annealing

As an effort to reduce the sintering time, IR annealing was studied by adding an IR lamp over a hot plate at 180 °C. Four different times (5, 10, 15 and 30 min) were evaluated and plotted the electrical resistivity Vs. time spent under the IR lamp (Figure 3.16).

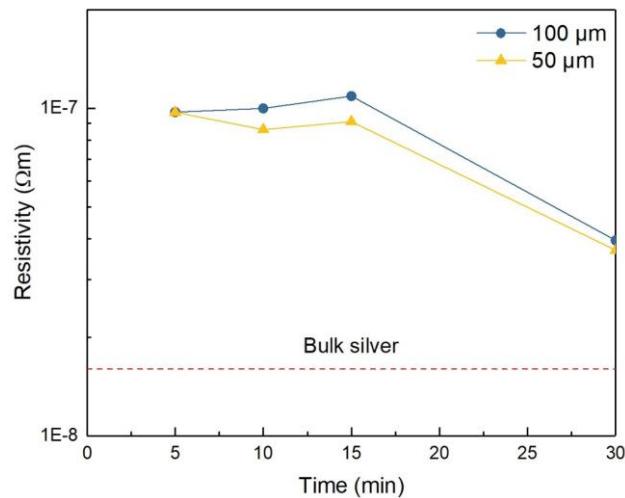


Figure 3.16- Resistivity Vs time plot for the different times (5, 10, 15 and 30 min) under the IR lamp.

From the figure above it is possible to detect, unexpectedly, that for both 100 and 50 μm lines the first three times (5, 10 and 15 min) have a small difference in electrical resistivity between them and for example, the 100 μm line sintered for 15 min has the highest one.

There are two possible reasons for this effect, one is that a printing error has occurred affecting the electrical performance or this sintering process is not very time-sensitive, but due to time constraints, it is not possible to perform an extensive study of this method.

When compared to thermal sintering this method enables the reduction of the sintering time, for example, a lower electrical resistivity was achievable in just 5 min under an IR lamp, when compared to conventional thermal sintering that requires 30 min to achieve that result. Therefore resulting in a must faster and cheaper process.

Another possible comparison is that for the same sintering time (30 min) it was achievable a similar electrical resistivity to the traditional thermal sintering process at 300 °C. This is justified by the extra heating energy provided from the IR lamp, making the overall temperature of the system (hot plate + IR lamp) higher than 180 °C originally defined by the hot plate. This extra heating energy is detrimental to the PVP that can burn easily as it can be seen in attachment G, so it is not viable for the final application to use that amount of time.

### 3.3 Electrical characterization of PVP layer

To guaranty, the insulating properties of the PVP layer the breakdown voltages for the different sintering conditions were calculated by applying 100 V to metal-insulator-metal samples, as Figure 3.17 shows, and measuring the current to plot the current density vs electric field graph (Figure 3.18 and Figure 3.19).

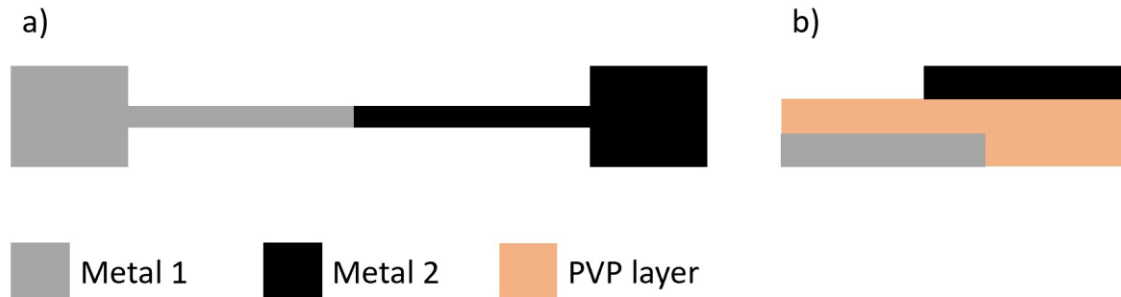


Figure 3.17- Test structure for calculating the breakdown voltage a) top view b) cross-section view

In all the different conditions it was not possible to reach the breakdown condition due to the limitation of the voltage source used (100 V), as Figure 3.18 and Figure 3.19 show. Nevertheless, from an application point of view, all three samples withstood 100 V without reaching the breakdown voltage and since the multilevel metallization scheme being developed in this work will be used for TFTs operating with significantly lower electric fields it is possible to guaranty the insulating properties of the PVP layer.

The results for the 180 °C for 30 min sintering condition (Figure 3.18 a)) shows a significant variance in the current density, this is caused by the differences in the area of the printed electrodes as attachment H shows and not caused by the deposition process of the insulating layer.

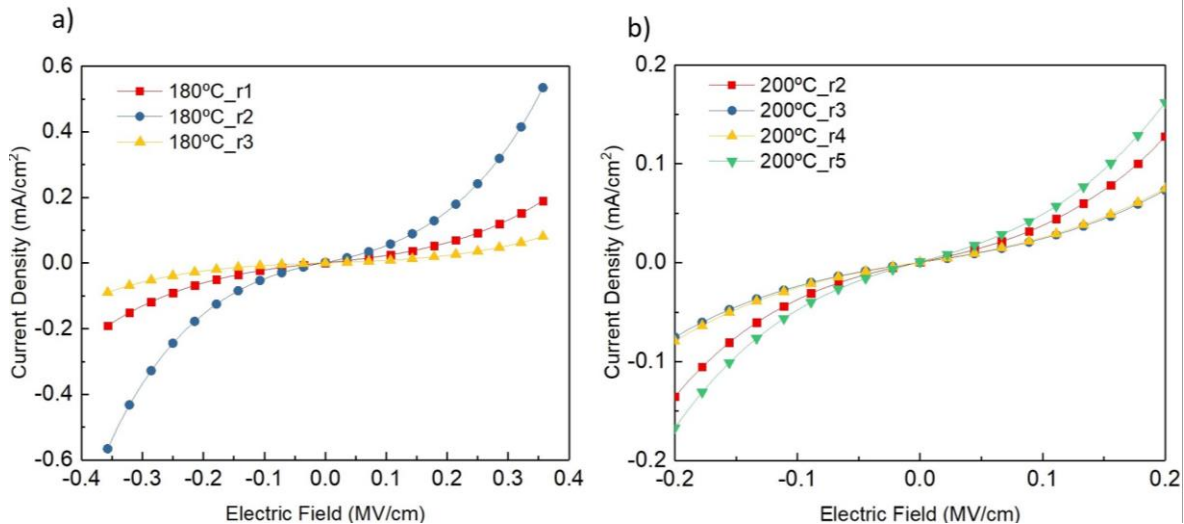


Figure 3.18- Graphics of the electric field Vs current density of the PVP films using thermal sintering methods; a) 180 °C for 30 min; b) 200 °C for 30 min.



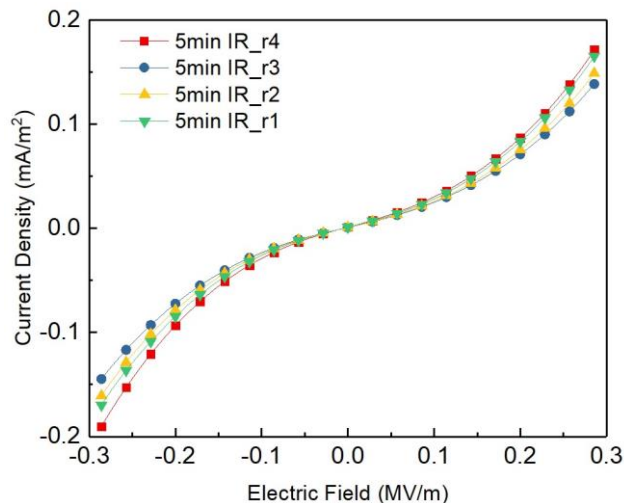


Figure 3.19- Graphic of the electric field Vs current density of the PVP films sintered at 5 min under an IR lamp.

Since both 180 °C and 5 min under the IR lamp sintering conditions produce printed patterns with similar electrical performances and both can insulate the different conductive layers, for an industrial application the IR method would be selected for being much faster.

### 3.4 Via formation and characterization

This section explains the via formation, the final profile obtained and the electrical characteristics. A printed pattern was utilized to mimic the final prototype because the removal of the PVP is very different when it is over glass or silver ink.

The pattern represented in attachment I has a blank square in the middle, representing a vacant spot of silver ink, in order to facilitate the removal of the PVP, due to the difficulties removing the polymer without destroying the silver underneath.

With this methodology, the connection between layers is done by the sidewalls of the hole. To guarantee that PVP is not present in the inner walls of the black square, the via dimensions will be slightly larger than the white square.

The two most relevant conditions (2.5 and 3 % power at 1 % speed) are represented in Figure 3.20.

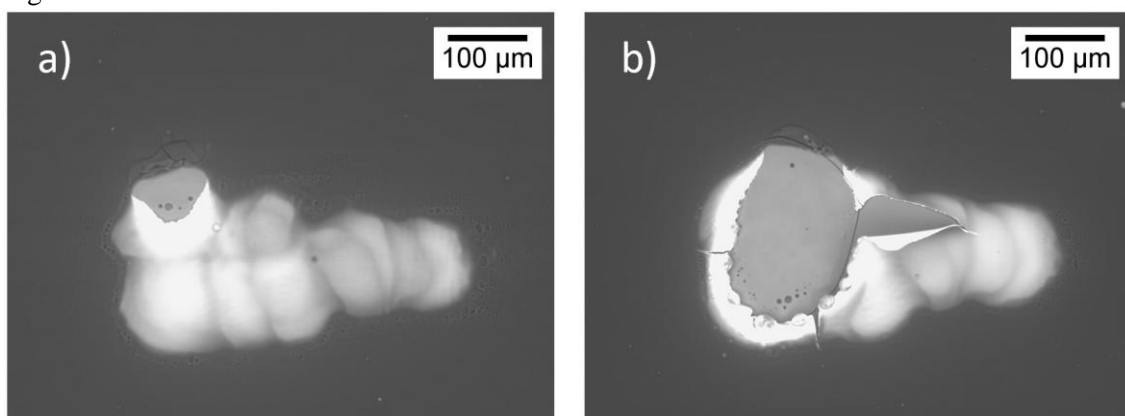


Figure 3.20- SEM images of the vias made by laser ablation; a) 2.5 % power and 1 % speed; b) 3 % power and 1 % speed.

By analyzing the figure above it is possible to observe that both conditions affect the PVP layer, the less powerful one in Figure 3.20a) it is able to remove a small amount of PVP, which could originate problems in the future, like PVP residue inside the via presenting it from

connecting the two levels of metallization. However, the more powerful condition in Figure 3.20b) that overly destroys the PVP lifting the silver from the glass, it is also undesirable.

To achieve the optimal condition, a compromise between the two conditions was tested, using the 3 % power but lowering the PPI from 1000 to 800 and an EDS analysis was performed to confirm that no PVP remains in the hole.

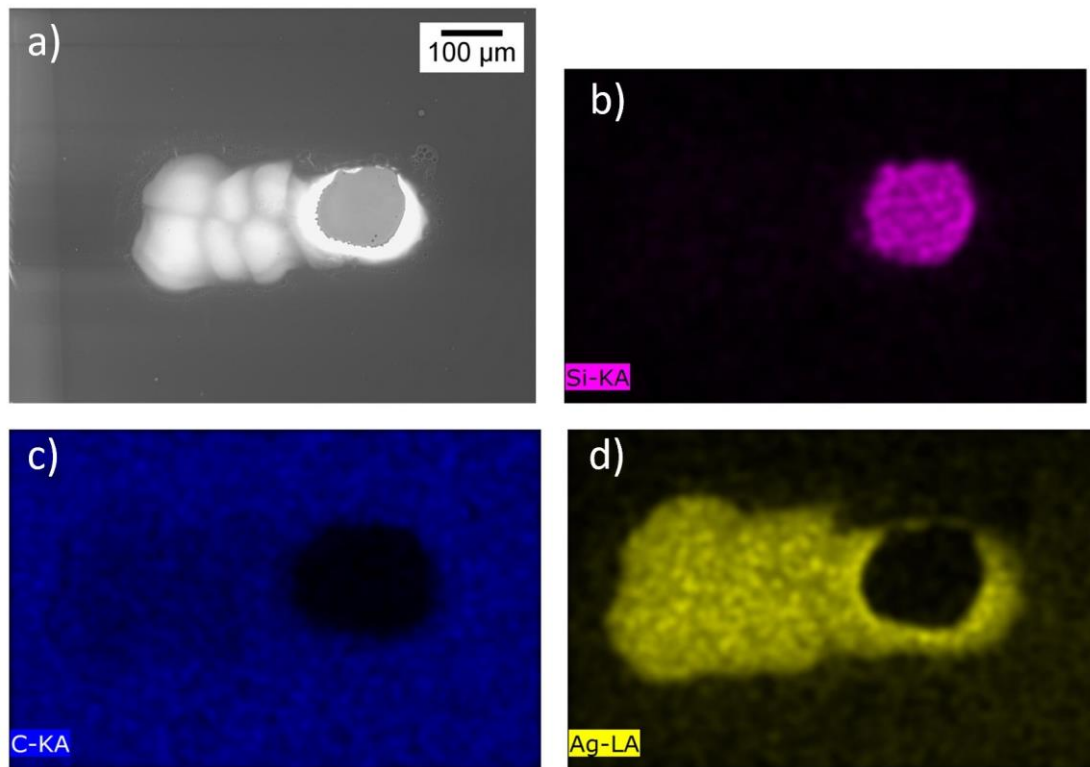


Figure 3.21- EDS mapping images of the via fabricated using 3 % power with 800 PPI at 1 % speed.

Figure 3.21 shows a completely vacant spot in the carbon signal of the EDS mapping (Figure 3.21c)), resulting in the removal of the PVP creating an electrical connection between the two conductive layers.

When analyzing Figure 3.21d) the same vacant spot is present, as intended, but a very slightly intensification of the signal around the bottom edge of the hole is present. This represents the enlargement of the hole mentioned above, due to the removal of some silver ink, ensuring the removal of PVP from the sidewalls of the hole.

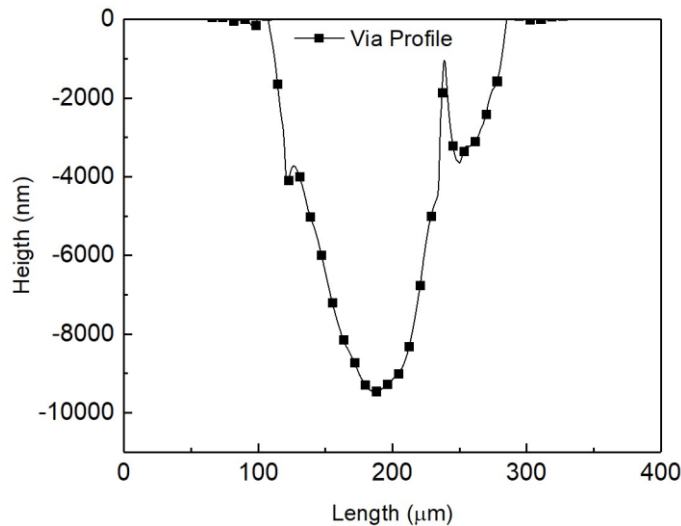


Figure 3.22- Profile of the via fabricated using 3 % power with 800 PPI at 1 % speed

Figure 3.22 shows a profile with a larger opening at the top. This facilitates the future filling the hole with silver ink, ensuring that all the side walls are covered allowing for a better electrical connection.

It is important highlighting the depth of the via that reached almost 10  $\mu\text{m}$  because the laser was able to destroy a little of the glass underneath and finally the small spike detected is caused by an unknown residue that at the time of measuring got trapped in the hole.

An important parament to determine is the resistance of the via itself. For that, a test structure was designed and it is represented in attachment J. This test structure was printed following the printing conditions discussed in section 3.1.1 for the first metal layer, followed by the deposition of the PVP, laser etching process and finally printing of the second metal layer following the conditions found in 3.1.3. Both metal layers were sintered at 200 °C for 30 min and a second sample was sintered for 5 min under an IR lamp.

The vias were filled ate the same time and with the same printing conditions as the second metal layer. In the design of that layer pads were drawn in the area of the via in order to fill them up and allow the connection between the two metal layers through the side walls of the hole.

To only obtain the resistance of the via the total resistance between the left and right pads was measured and then subtracted the resistance of the two metal layers (measured individually), as the following equation shows.

$$R_T = R_{M1} + R_{M2} + R_{via}$$

Were  $R_T$  is the total resistance of the printed pattern,  $R_{M1}$  and  $R_{M2}$  are the resistance of the first and second layer respectively and finally,  $R_{via}$  is the resistance of the via connecting the two layers and that value is shown in the Table 3.11.

Table 3.11- Calculated value for the resistance of the via for the two sintering conditions studied

Conditions	$R_T$	$R_{via}$
200 °C	32.28	0.15
5 min IR	24.70	0.82

From Table 3.11 is possible to observe that in both conditions the resistance of the via is very low and compared to the total resistance can be considered insignificant.

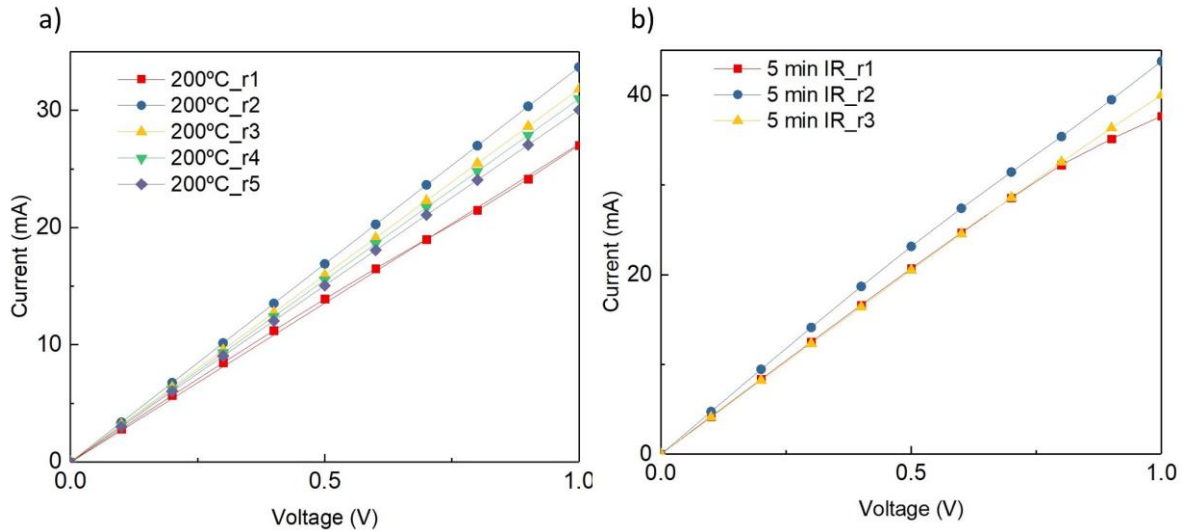


Figure 3.23- I-V curves of the total resistance of the test structure utilized sintered at; a) 200 °C; b) 5 min under the IR lamp.

To guaranty reproducibility of the process, several parallel samples were tested and the results shown in Figure 3.23. The small variance observed are due to alignment errors in the laser etching process, because this alignment is done by hand, or caused by alignment errors when printing the second metal layer. Nevertheless, those variances are within statistical acceptance, confirming the reproducibility of the process.

### 3.5 Final prototype

To fabricate the TFTs it was first necessary to design a mask layout, represented in Figure 3.24 and following a process already established in CENIMAT<sup>27</sup>. This mask layout comprises TFTs with a width to length ration of 40/10 ( $\mu\text{m}/\mu\text{m}$ ) and source, drain and gate contact pads were dimensioned to be compatible with the via formation process described in the previous section ( $500 \times 500 \mu\text{m}^2$ ). The total mask layout occupies an area of  $12.25 \text{ cm}^2$  and includes 220 TFTs with the layout depicted below.

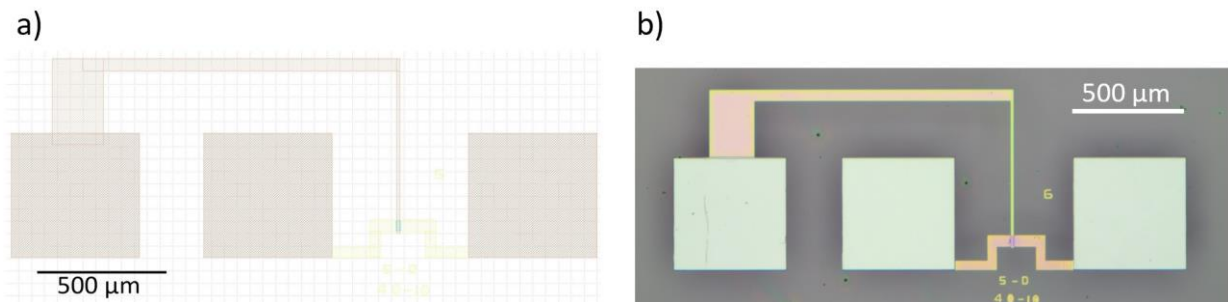


Figure 3.24- a) Mask layout of one oxide TFT for the final prototype b) one oxide TFT fabricated in clean-room.

The final prototype will have a similar cross-section as shown in Figure 3.25 and it is possible to detect that the TFTs are passivated with parylene. As such, surface for conductive ink printing is again different from glass, requiring the confirmation if printing conditions would be adequate for printing Ag lines with the required linewidths and electrical properties.

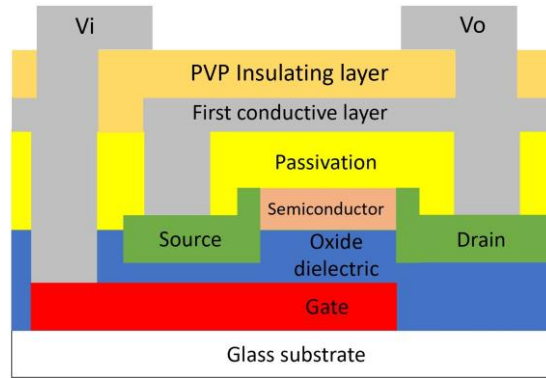


Figure 3.25- schematic of the cross-section of one TFT with two levels of metallization.

As in section 3.1.3, the printing conditions used on glass were tested and the results are represented in Figure 3.26 and Table 3.12.

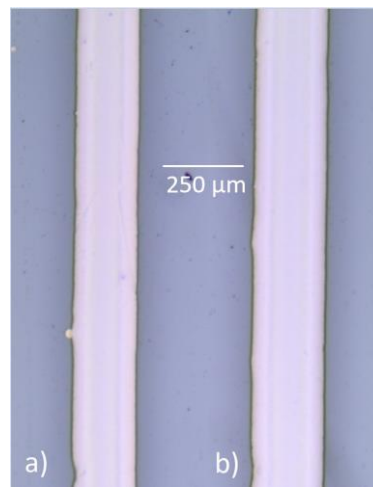


Figure 3.26- Silver lines printed on parylene with substrate temperature of 50 °C, speed of 50 mm/s and 750 DPI a) 50 µm b) 100 µm.

The Figure 3.26 shows that is very difficult to distinguish the 50 (Figure 3.26a)) from the 100 (Figure 3.26b)) µm line and suffered a significant increase in the line width, but in terms gained a better uniformity, as the average width and standard deviation from Table 3.12 confirms.

Table 3.12- Width of the silver lines printed on parylene with substrate temperature of 50 °C, speed of 50 mm/s and 750 DPI.

Lines	Average Width	Standard Deviation
<b>100 µm</b>	227.98	7.60
<b>50 µm</b>	198.67	2.50

To solve this problem, it is possible to change the dimensions of the pattern in the software but since the parylene appears to have similar surface properties as the PVP, utilize the optimal printing condition for the PVP is the more logical solution. Those results are summarized in Figure 3.27 and Table 3.13.

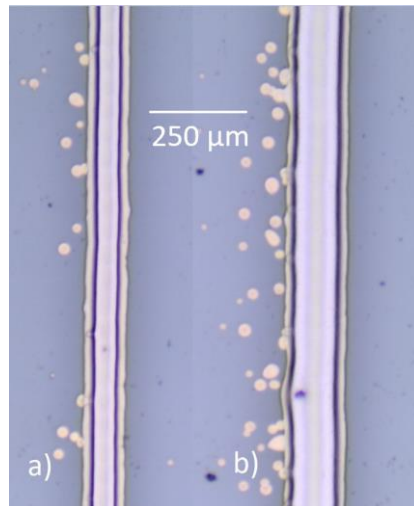


Figure 3.27 Silver lines printed on parylene with substrate temperature of 50 °C, speed of 50 mm/s and 400 DPI with 3 layers; a) 50 μm b) 100 μm.

With this printing conditions is evident the size difference between the 50 (Figure 3.27a) and 100 (Figure 3.27b)) μm lines while keeping the almost perfect uniformity, as the standard deviations from the Table 3.13 shows. However, the values for the width of both lines continue outside the desired range, so a pattern reduction is necessary.

Table 3.13- Width of the silver lines printed on parylene with substrate temperature of 50 °C, speed of 50 mm/s and 400 DPI with 3 layers

Lines	Average Width (μm)	Standard Deviation
100 μm	157.17	3.20
50 μm	106.22	5.60

Besides the line morphology, it is important to verify if the electrical properties are not affected. As Figure 3.28 shows, both 50 and 100 μm lines are not significantly affected by the different printing conditions.

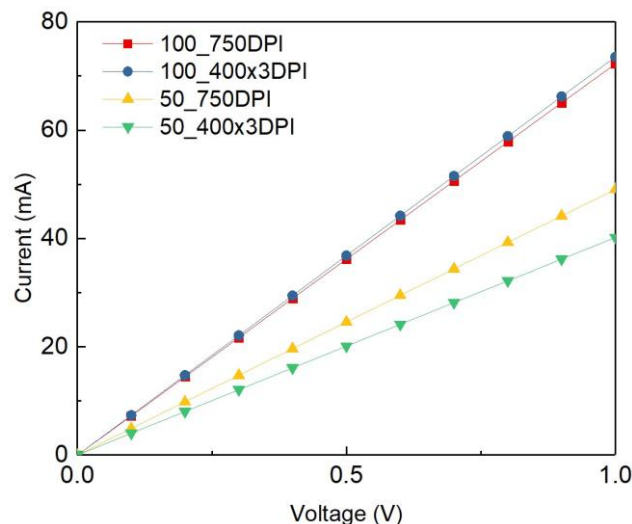


Figure 3.28- I-V curves of the silver lines printed on parylene, comparing the two different printing conditions

With the printing condition confirmed, printing patterns of each digital circuit blocks were designed. As a proof of concept several circuit blocks will be tested, like a universal

NAND logic gate, a simple inverter and inverters with 2 and 3 drive TFTs in parallel. The pattern for those circuit blocks is represented in attachment K.

All the patterns were fabricated following the procedure explained in section 2.5. Starting by connecting different TFTs in parallel, the Figure 3.29a) shows that when connecting 3 TFTs in parallel the current is 4.8 times of a single TFT when it was expected to be only 3 times. This can be justified by the significant difference in performance between discrete TFTs as Figure 3.29b) shows.

Next, a simple inverter with 2 TFTs was tested and Figure 3.29c) shows the correct transfer curve for this type of logic gate. Nevertheless, is possible to observe that the  $V_{OL}$  is around 1.5 V which is expected because both TFT are n-type and have the exact same dimensions. In order to solve this problem more drive transistors were added in parallel in order to decrease the drive resistance and lower the  $V_{OL}$  to around 0.5 V, thus enhancing the logic swing compared to the 2 TFTs inverter. This also means that the Ag printed lines are working as intended and not affecting the performance of the digital circuit blocks.

The final digital circuit block tested was a universal NAND gate and the transfer curve can be seen in Figure 3.29d) with the expected behavior from this type of logic gate. It is also possible to observe that this inverter like behavior stays the same with different  $V_{DD}$  values. The major problem is once again the high  $V_{OL}$  for the same reasons explained above and the solutions would be the same by increasing the number of drive TFTs.

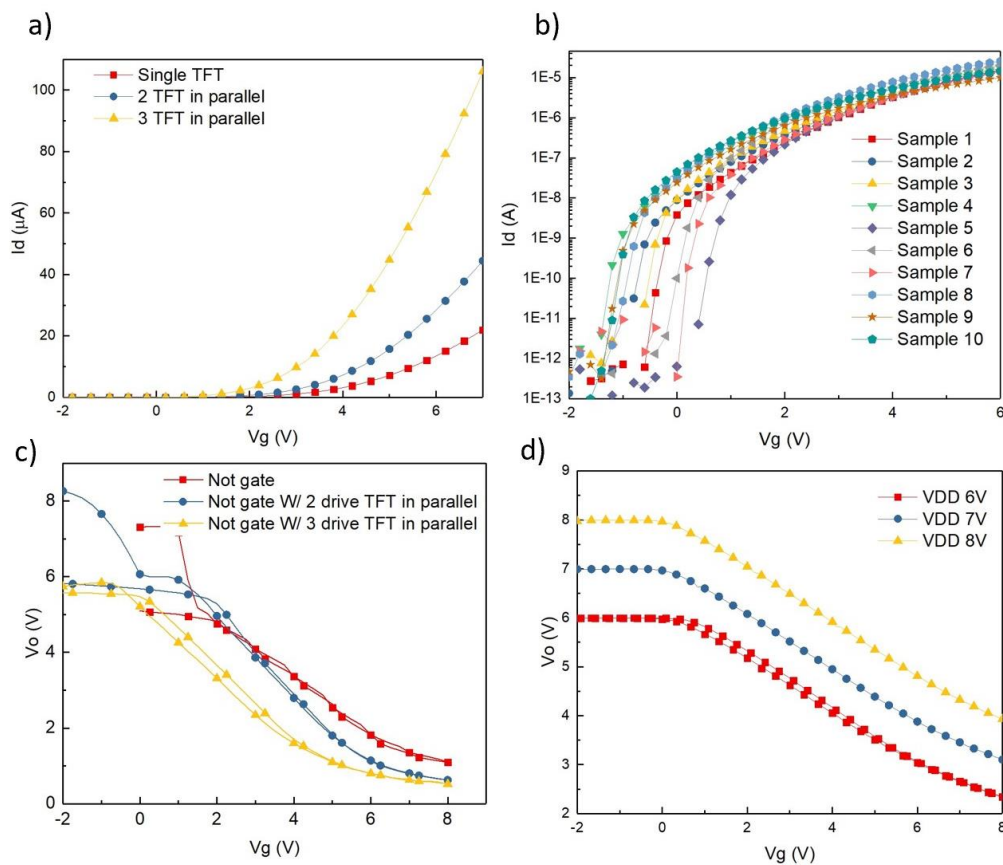


Figure 3.29- Transfer curves for a) different TFTs in parallel with  $V_{DD} = 6$  V; b) 10 discrete oxide TFTs with  $V_{DD} = 5$  V; c) not gates with different number of drive transistors and  $V_{DD} = 6$  V; d) NAND gate at different  $V_{DD}$  values.





## 4. Conclusions and future perspectives

In summary, this dissertation describes the development of a printed multi-level metallization process to interconnect oxide-based TFTs in several digital circuit blocks. This was achieved by optimizing the printing conditions on glass, in order to reliably print 100 and 50  $\mu\text{m}$  wide silver lines with the biggest cross-sectional area possible, maximizing the electrical performance. With a substrate temperature of 50 °C, 750 DPI and 50 mm/s speed it was achievable line width of  $106.89 \pm 14.86$  and  $66.5 \pm 12.57$   $\mu\text{m}$ .

In the future to reduce the line edge roughness, it is necessary to refine the printing conditions and control the humidity and temperature in the laboratory, guaranteeing a more precise and consistent printing process.

In order to print two or more conductive layers, it is necessary to deposit an insulating material between the different metallization levels. To achieve this a 4  $\mu\text{m}$  thick PVP film was deposited allowing a metal-insulator-metal stack to operate up to 100 V without reaching breakdown. As future development, achieving a more uniform and reproducible PVP film would be desirable and for that end conduct a more in-depth study or for example, utilize a commercially available insulating ink designed for these applications.

After depositing the insulating layer, a new conductive layer is printed but now on top of PVP, which naturally has different surface properties compared to glass, resulting in a change of the printing conditions yielding line widths of  $202.66 \pm 13.08$  and  $90.11 \pm 13.02$   $\mu\text{m}$  by using three printed layers with 400 DPI each at a speed of 50 mm/s. Since the objective is to have the smallest line width possible, those are outside the defined range and to solve that the pattern layout must be reduced by half in the software.

For the printed lines to be conductive, a thermal sintering method and a combination of thermal with photonic curing assisted by an IR lamp were applied. The optimal condition, that allowed for a balance between temperature and time of the process while keeping a good electrical resistivity was 200 °C for 30 min on a hot plate, achieving  $7.12 \times 10^{-8}$   $\Omega\text{m}$  which is 4.5 times the bulk value for silver. Meanwhile, with the IR sintering method, a significant reduction in the sintering time (from 30 min to 5 min) at the expense of losing 37 % of electrical performance was achieved. To achieve electrical resistivities closer to the bulk value it would be necessary to perform a more in-depth study, especially for the IR sintering method or apply alternative sintering methods like microwave, flash or laser sintering.

For this stage in development, a laser etching process was applied to connect the two different levels of metallization, by selecting removing the PVP film using an optimal condition of 800 PPI with 3 % power at 1 % speed, creating a via with a diameter of 100  $\mu\text{m}$  and a resistance lower than 1  $\Omega$ . In future works, a more refined optimization should be performed in order to control the variance still present and reducing the sensitivity to changes of material and in laboratory conditions.

Finally, it was possible to put all those individual steps together and demonstrate a proof of concept by fabricating different digital circuit blocks (inverter and NAND gate) with the expected behaviour and very good performance even with significant difference in performance of individual TFTs. This processes allows for the user to choose which TFT has the desired characteristics for the prototype in mind. In a next step, more complex electrical circuits with more layers and complex interconnections could arise. An interesting study would be to confirm if it is possible to remove all the interconnections without affecting the TFTs, allowing a new prototype to be printed on the same substrate, making the TFT substrate reusable.



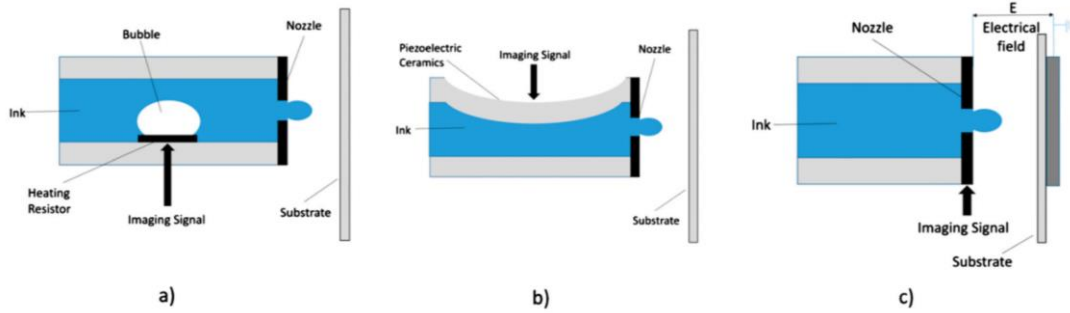
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## 6. Attachments

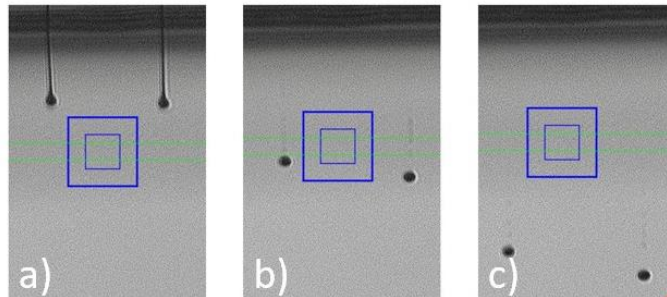
**Attachment A-** DOD inkjet printing: a) thermal, b) piezoelectric, c) electrostatic<sup>2</sup>



**Attachment B-** Summary of the two best values for each variable in the study

Substrate temperature (°C)	Speed (mm/s)	DPI
30	50	750
50	100	1000

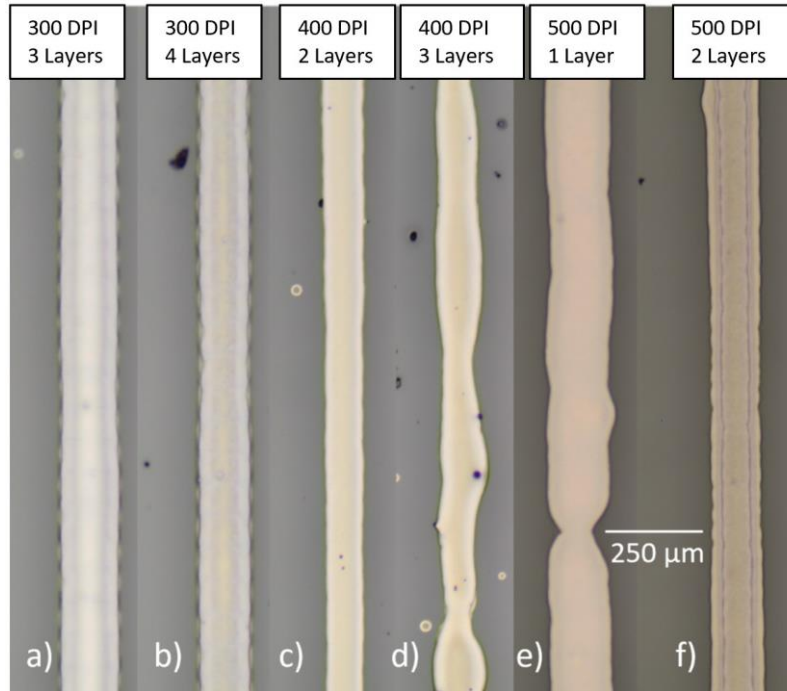
**Attachment C-** Time laps of the droplet formation under 50 % humidity environment with higher voltage values



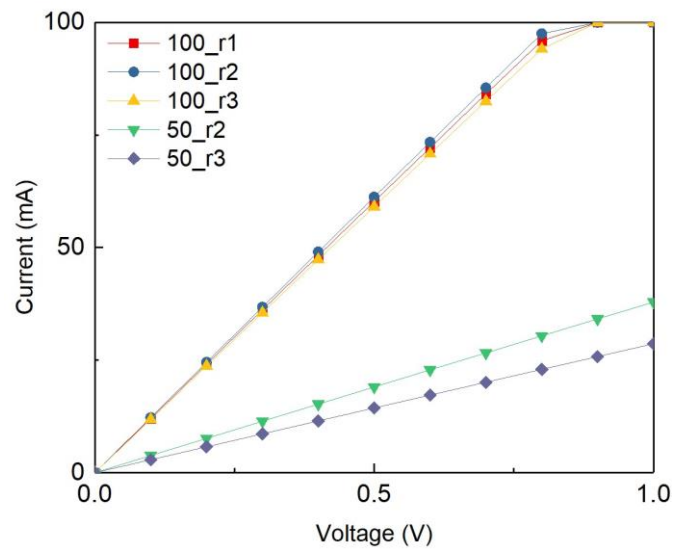
**Attachment D-** Electrical resistivity for the 50 μm line with different DPIs and number of printed layers.

Condition		Width (μm)		Thickness (nm)		Resistance (Ω)	Resistivity (Ωm)
DPI	Number of layers	Average	Standard deviation	Average	Standard deviation		
300	3	134.72	20.61	268.67	35.42	149.48	$5.41 \times 10^{-7}$
	4	124.35	8.98	420.33	59.04	238.88	$1.24 \times 10^{-6}$
400	2	102.20	6.70	331.67	15.21	>10 <sup>9</sup>	>10
	3	90.11	13.02	536.56	48.57	50.40	$2.44 \times 10^{-7}$
500	1	165.23	8.17	119.88	7.19	2426.00	$4.81 \times 10^{-6}$
	2	126.38	7.79	347.78	37.23	293.22	$1.29 \times 10^{-6}$

**Attachment E-** 50 μm Ag line printed on PVP with a substrate temperature of 50 °C and a speed of 50 mm/s.



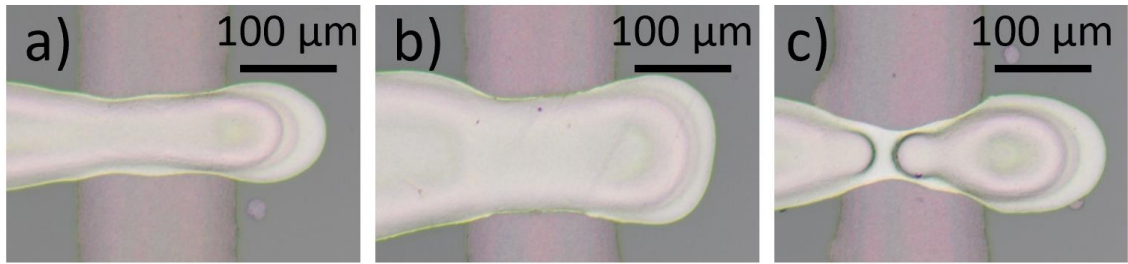
**Attachment F-** I-V curve showing the reproducibility of the selected sintering condition (200 °C for 30 min on a hot plate).



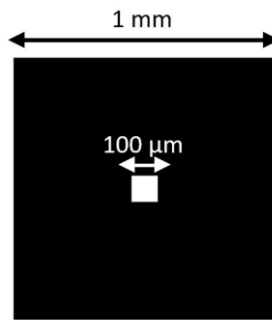
**Attachment G-** Burned PVP film caused by a lengthy treatment under an IR lamp.



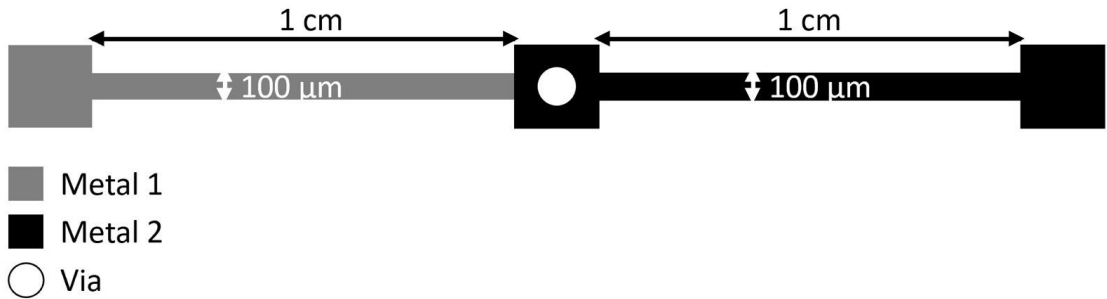
**Attachment H-** Overlapping areas of the three parallel samples sintered at 180 °C for 30 min on a hot plate.



**Attachment I-** Test structure for optimizing the via formation.



**Attachment J-** Test structure for obtaining the resistance of the via



**Attachment K-** Pattern of the multi-level interconnections for each digital circuit block being produced; a) 3 and 2 TFT connected in parallel; b) simple inverter; c) inverter with 2 drive TFTs in parallel; d) inverter in 3 drive TFTs in parallel; e) NAND logic gate.

